

TMS320F20x/F24x DSP Embedded Flash Memory Technical Reference

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About This Manual

This reference guide describes the operation of the embedded flash EEPROM module on the TMS320F20x/F24x digital signal processor (DSP) devices and provides sample code that you can use in developing your own software. The performance specifications of the embedded flash memory have been evaluated using the algorithms and techniques described in this guide. TI does not recommend deviation from these algorithms and techniques, since doing so could affect device performance. The book does not describe the use of any specific flash programming tool nor does it describe the external interface to the DSP. For information about any aspect of the TMS320F20x/F24x devices other than the embedded flash EEPROM module, see *Related Documentation from Texas Instruments* on page v.

How to Use This Manual

There are several stand-alone flash programming tools for TMS320F20x/F24x generation of DSPs. Using one of these stand-alone tools with the TMS320F20x/F24x requires only a basic understanding of the flash operations. More information about these flash programming tools is available on the TI web page, <http://www.ti.com>. This guide is intended to provide a complete understanding of the flash operations. This level of understanding is necessary for making modifications to existing flash programming tools or for developing alternative programming schemes.

If you are looking for information about:	Turn to these locations:
Algorithms	Chapter 3, <i>Algorithm Implementations and Software Considerations</i>
Erasing the flash array	Section 1.1, <i>Basic Concepts of Flash Memory Technology</i> Section 2.1, <i>Modifying the Contents of the TMS320F20x/F24x Flash Array</i> Section 2.6, <i>Erase Operation</i> Section 3.3, <i>Erase Algorithm</i>

If you are looking for information about:	Turn to these locations:
Over-erasure (depletion) and recovery	Section 1.1, <i>Basic Concepts of Flash Memory Technology</i> Section 2.7, <i>Recovering From Over-Erasure (Flash-Write Operation)</i> Section 3.4, <i>Flash-Write Algorithm</i>
Programming the flash array	Section 1.1, <i>Basic Concepts of Flash Memory Technology</i> Section 2.1, <i>Modifying the Contents of the TMS320F20x/F24x Flash Array</i> Section 2.5, <i>Program Operation</i> Section 3.2, <i>Programming Algorithm</i>
Sample code	Appendix A, <i>Assembly Source Listings and Program Examples</i>

Notational Conventions

This document uses the following conventions.

- The flash EEPROM is referred to as flash memory or the flash module. The term flash array refers to the actual memory array within the flash module. The flash module includes the flash memory array and the associated control circuitry.
- The DSP generation and devices are abbreviated as follows:
 - TMS320F20x/24x generation: 'F20x/24x
 - TMS320F20x devices: 'F20x
 - TMS320F24x devices: 'F24x
- Program listings and code examples are shown in a special type-face.

Here is a sample program listing:

```
0011 0005 0001      .field    1, 2
0012 0005 0003      .field    3, 4
0013 0005 0006      .field    6, 3
0014 0006           .even
```

Related Documentation From Texas Instruments

The following books describe the 'F20x/24x and related support tools. To obtain a copy of any of these TI documents, call the Texas Instruments Literature Response Center at (800) 477–8924. When ordering, please identify the book by its title and literature number.

TMS320C24x DSP Controllers Reference Set, Volume 1: CPU, System, and Instruction Set (literature number SPRU160) describes the TMS320C24x 16-bit, fixed-point, digital signal processor controller. Covered are its architecture, internal register structure, data and program addressing, and instruction set. Also includes instruction set comparisons and design considerations for using the XDS510 emulator.

TMS320C24x DSP Controllers Reference Set Volume 2: Peripheral Library and Specific Devices (literature number SPRU161) describes the peripherals available on the TMS320C24x digital signal processor controllers and their operation. Also described are specific device configurations of the 'C24x family.

TMS320C240, TMS320F240 DSP Controllers (literature number SPRS042) data sheet contains the electrical and timing specifications for these devices, as well as signal descriptions and pinouts for all of the available packages.

TMS320C2x/C2xx/C5x Optimizing C Compiler User's Guide (literature number SPRU024) describes the 'C2x/C2xx/C5x C compiler. This C compiler accepts ANSI standard C source code and produces TMS320 assembly language source code for the 'C2x, 'C2xx, and 'C5x generations of devices.

TMS320F206 Digital Signal Processor (literature number SPRS050) data sheet contains the electrical and timing specifications for the 'F206 device, as well as signal descriptions and the pinout.

TMS320F241, TMS320C241, TMS320C242 DSP Controllers (literature number SPRS063) data sheet contains the electrical and timing specifications for the 'F241, 'C241, and 'C242 devices, as well as signal descriptions and pinouts.

TMS320F243 DSP Controller (literature number SPRS064) data sheet contains the electrical and timing specifications for the 'F243 device, as well as signal descriptions and the pinout.

TMS320C2xx User's Guide (literature number SPRU127) discusses the hardware aspects of the 'C2xx 16-bit, fixed-point digital signal processors. It describes the architecture, the instruction set, and the on-chip peripherals.

TMS320C2xx C Source Debugger User's Guide (literature number SPRU151) tells you how to invoke the 'C2xx emulator and simulator versions of the C source debugger interface. This book discusses various aspects of the debugger interface, including window management, command entry, code execution, data management, and breakpoints. It also includes a tutorial that introduces basic debugger functionality.

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Introduction

The TMS320F20x/F24x digital signal processors (DSPs) contain on-chip flash EEPROM (electrically-erasable programmable read-only memory). The embedded flash memory provides an attractive alternative to masked program ROM. Like ROM, flash memory is nonvolatile, but it has an advantage over ROM: *in-system* reprogrammability.

This chapter discusses basic flash memory technology, introduces the flash memory module of the 'F20x/F24x DSP, and lists the benefits of flash memory embedded in a DSP chip.

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1.1 Basic Concepts of Flash Memory Technology

The term flash in this EEPROM technology refers to the speed of some of the operations performed on the memory (these operations will be described in greater detail later in this document). An entire block of bits is affected simultaneously in a *block* or *flash operation*, rather than being affected one bit at a time. In contrast, writing data to the flash memory cannot be a block operation, since normally a selection of ones and zeroes are written (all bits are not the same value). Writing selected bits to create a desired pattern is known as programming the flash memory, and a written bit is called a programmed bit.

Several different types of program and erase operations are performed on the flash memory in order to properly produce the desired pattern of ones and zeroes in the memory. It should be noted that, under some conditions, flash memory may become overerased, resulting in a condition known as depletion. The 'F20x/F24x algorithms avoid overerasure by using an approach that erases in small increments until complete erasure is achieved.

The 'F20x/F24x flash EEPROM includes a special operation, flash-write, that is used only to recover from over-erasure. Because of the implementation of the flash memory, when over-erasure occurs, any particular bit in depletion mode is difficult to identify. For this reason, the 'F20x/F24x simply writes an entire block of bits simultaneously; hence, the name flash-write.

The program and erase operations in flash memory must provide sufficient charge margin on 1s and 0s to ensure data retention, so the 'F20x/F24x flash module includes a hardware mechanism that provides margin for erasing or programming. This mechanism implements voltage reference levels which ensure this logic level margin when modifying the contents of the flash memory.

1.2 TMS320F20x/F24x Flash Module

The 'F20x/F24x flash EEPROM is implemented with one or two independent flash memory modules of 8K or 16K words. Each flash module is composed of a flash memory array, four control registers, and circuitry that produces analog voltages for programming and erasing. The flash array size of the TMS320F206 and TMS320F240 is 16K × 16 bits, while the TMS320F241 and TMS320F243 incorporate an 8K × 16-bit flash array (see Table 1–1). Unlike most discrete flash memories, the 'F20x/F24x flash module does not require a dedicated state machine, because the algorithms for programming and erasing the flash are executed in software by the DSP core. The use of these sophisticated, adaptive programming algorithms results in reduced chip size and greater programming flexibility. In addition, the application code can manage the use of the flash memory without the requirement of external programming equipment.

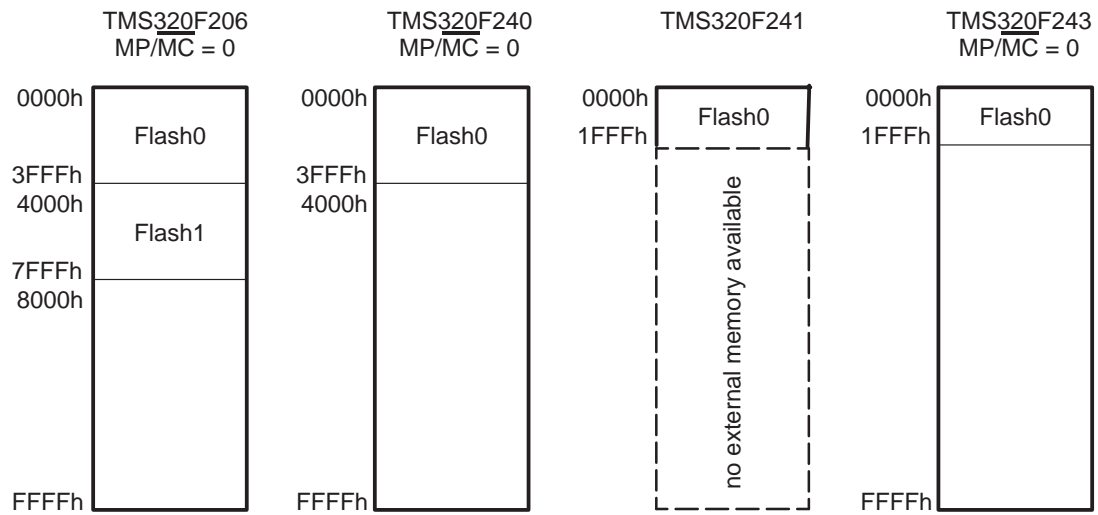
Table 1–1. TMS320 Devices With On-Chip Flash EEPROM

Device	Array Size	Total Flash Memory
TMS320F206	16K	32K [†]
TMS320F240	16K	16K
TMS320F241	8K	8K
TMS320F243	8K	8K

[†] Each array can be independently erased.

Simplified memory maps for the program space of the TMS320F20x/F24x devices are shown in Figure 1–1 to illustrate the location of the flash modules.

Figure 1–1. TMS320F20x/F24x Program Space Memory Maps



1.3 Benefits of Embedded Flash Memory in a DSP System

The circuitry density of flash memory is about half that of conventional EEPROM memory, making it possible to approach DRAM densities with flash memory. This increased density allows flash memory to be integrated with a CPU and other peripherals in a single 'F20x/F24x DSP chip. Embedded flash memory expands the capabilities of the 'F20x/F24x DSPs in the areas of prototyping, integrated solutions, and field upgradeable designs.

Embedded flash memory facilitates system development and early field testing. Throughout the development process, the system software can be updated and reprogrammed into the flash memory for testing at various stages. Since flash is a non-volatile memory type, the resulting standalone prototype can be tested in the appropriate environment without the need for battery backup. In addition to its nonvolatile nature, embedded flash memory has the advantage of in-system programming. Unlike some discrete flash or EEPROM chips, embedded flash memory can be programmed without removing the device from the system board. In fact, the embedded flash memory of 'F20x/F24x DSPs can be programmed using hardware emulators which are already an integral part of the DSP development process; no external programming equipment is required.

The embedded flash memory of 'F20x/F24x DSPs also makes these devices ideal for highly integrated, low-cost systems. The initial investment involved with making a ROM memory is not justifiable for certain low-cost applications. Accordingly, when on-chip ROM is not an option, DSP system designers usually resort to using expensive static RAM (SRAM), to store system software and data. The SRAM provides the fast access times required by the DSP, but has the disadvantage of being a volatile memory type. To address the issue of memory volatility, designers often use a low-cost EPROM or flash device to load the SRAM after system power-up. This approach is very expensive, and the increased chip count is often prohibitive. The 'F20x/F24x DSPs, with their on-chip flash memory modules, provide a single chip solution with nonvolatile memory that supports full speed DSP access rates.

Another benefit of embedded flash memory in a DSP system is remote reprogrammability. Field upgradeability is an extremely useful feature for embedded systems. For example, many modem manufacturers offer algorithm upgrades remotely, without requiring the modem to be removed from the host computer system. The same type of feature is also being offered for many handheld consumer products. Adding this capability to a product requires the addition of EEPROM or flash devices, which increase chip count and system cost. Since no external equipment is required to program the embedded flash memory of the 'F20x/F24x DSPs, these devices enable field upgradeability without impacting system cost.

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Flash Operations and Control Registers

The operations that modify the contents of the 'F20x/F24x flash array are performed in software through the use of dedicated programming algorithms. This chapter introduces the operations performed by these algorithms and explains the role of the control registers in this process. The actual algorithms are discussed in Chapter 3.

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2.1 Operations that Modify the Contents of the 'F20x/F24x Flash Array

Operations that modify the contents of the flash array are generically referred to as either “programming,” which drives one or more bits toward the logic zero state, or “erasing,” which drives all bits towards the logic one state. It should be noted that since these operations are performed incrementally, a single “programming” or “erasing” operation does not ALWAYS result in a valid logic one or zero. The result of each of these types of operations depends on the initial state of the bit(s) prior to the operation. This is described in more detail below.

Within these two basic types of operations (which are related to the fact that there are only two valid logic levels in the F20x/F24x device) are four distinctly different types of functions which are actually performed.

In the category of “programming” operations, there are three actual types of functions that are performed:

- Clear – which is used to write ALL array bits to a zero state,
- Program – which is used to write SELECTED array bits to zero, and
- Flash-Write – which is used to recover ALL array bits from depletion

In the category of “erase” operations, there is only one type of operation:

- Erase – which is used to write ALL array bits to a one state.

Clear, Program, Flash-Write, and Erase are the only four functions that are used to modify the flash array.

Assuming that the intent of a modification of the contents of the flash array is to program the array with a selection of ones and zeroes, the following sequence of operations must be performed for proper operation of the flash memory:

- 1) The array is first CLEARED to all zeroes.
- 2) The array is then ERASED to all ones.
- 3) The array is then checked for depletion and recovered using FLASH-WRITE if necessary (note that if Flash-Write is used to recover from depletion, this sequence must be started over again with the Clear and Erase functions).
- 4) Once the array is properly cleared and erased, and verified not to be in depletion, the array is then PROGRAMMED with the desired selection of zero bits.

This procedure is discussed in complete detail in Chapter 3.

During these operations that are used to modify the contents of the flash array, three special read modes, and a corresponding set of reference voltage levels, are used when reading back data values to verify programming and erase operations.

These read modes and reference levels are:

- VER0 – which is used to verify the logic zero level including margin,
- VER1 – which is used to verify the logic one level including margin, and
- Inverse Erase – which is used to verify depletion recovery.

These concepts are illustrated graphically in Figure 2–1 and summarized in Table 2–1.

Note that **ONLY** the Erase and the Flash-Write functions are truly “flash” in the sense that these functions actually affect all bits in the array simultaneously. In contrast, bit programming levels in the Program and Clear functions can be controlled individually on a bit-by-bit basis.

Therefore, when using the Erase or Flash-Write functions, the whole array is modified, and then the whole array is read, word by word, to verify whether all words have reached the same value (if not, further iterations of the Erase or Flash-Write functions continue).

In these cases, as mentioned previously, all the bits in the array are modified simultaneously, but some bits may react more quickly, potentially resulting in variation in actual levels on different bits. Therefore, when performing an Erase, it is possible that some bits may reach depletion even before other bits reach the logic one reference level (VER1).

The reason that it is critical to clear the array to a consistent zero level before erasing the array is to give maximum immunity to depletion when erasing. Note, however, that even when following this sequence, some flash arrays may experience depletion, and may require recovery using the Flash-Write function.

In contrast to the true “flash” operations Erase and Flash-Write, after each incremental Program or Clear operation, each bit is tested against the VER0 reference level to determine the exact point at which it has reached the proper value, following which, no further incremental adjustment of the level is made on that bit. Therefore, when the Program or Clear operation is complete, all bits are at the same zero level, which greatly increases proper data retention and depletion immunity for the device. Again, note that the programming and erase operations are discussed in complete detail in Chapter 3.

Figure 2–1. Flash Memory Logic Levels During Programming and Erasing

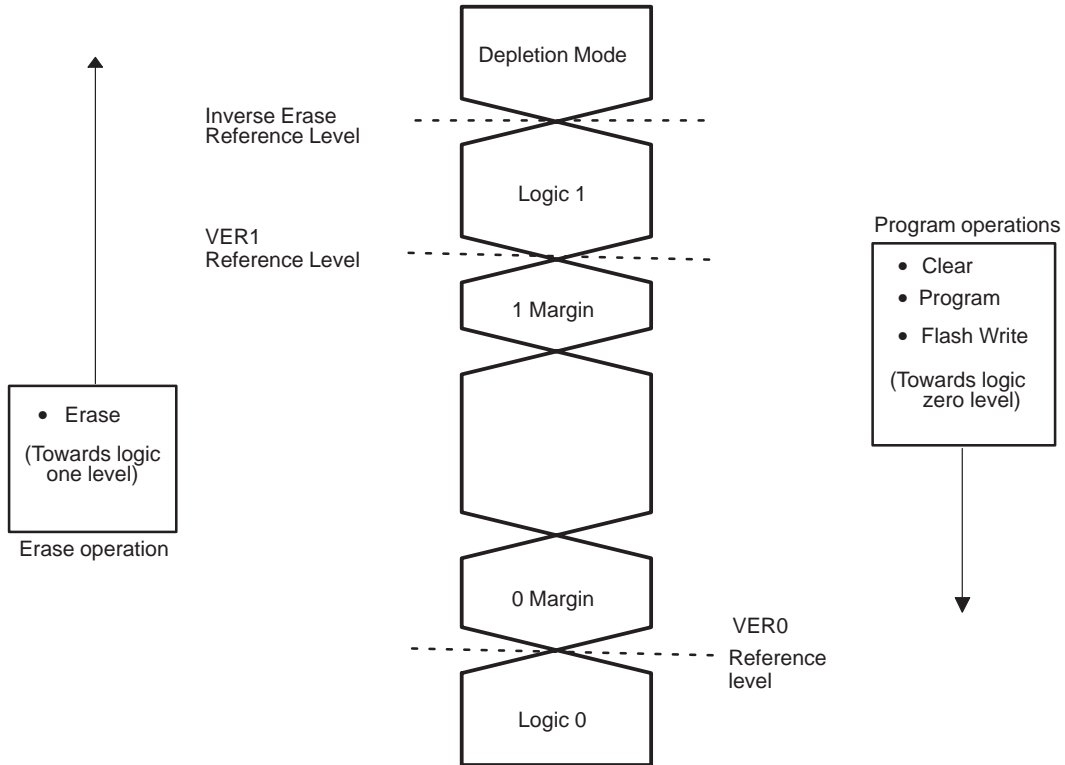


Table 2–1. Operations that Modify the Contents of the Flash Array

Change in Bit Level			
Towards Logic 1		Towards Logic 0	
Function	Reference Level	Function	Reference Level
Erase (all bits)	VER1	Program (selected bits)	VER0
		Clear (all bits)	VER0
		Flash-Write (all bits)	Inverse Erase

2.2 Accessing the Flash Module

In addition to the flash memory array, each flash module has four registers that control operations on the flash array. These registers are:

- Segment control register (SEG_CTR)
- Test register (TST)
- Write address register (WADRS)
- Write data register (WDATA)

The flash module operates in one of two modes: one in which the flash memory is accessed directly by the CPU, and one in which the memory array cannot be accessed directly, but the four control registers are accessible. This mode is used for programming. Each flash module has a flash access-control register that selects between these two access modes. The register is a single-bit, I/O-mapped register.

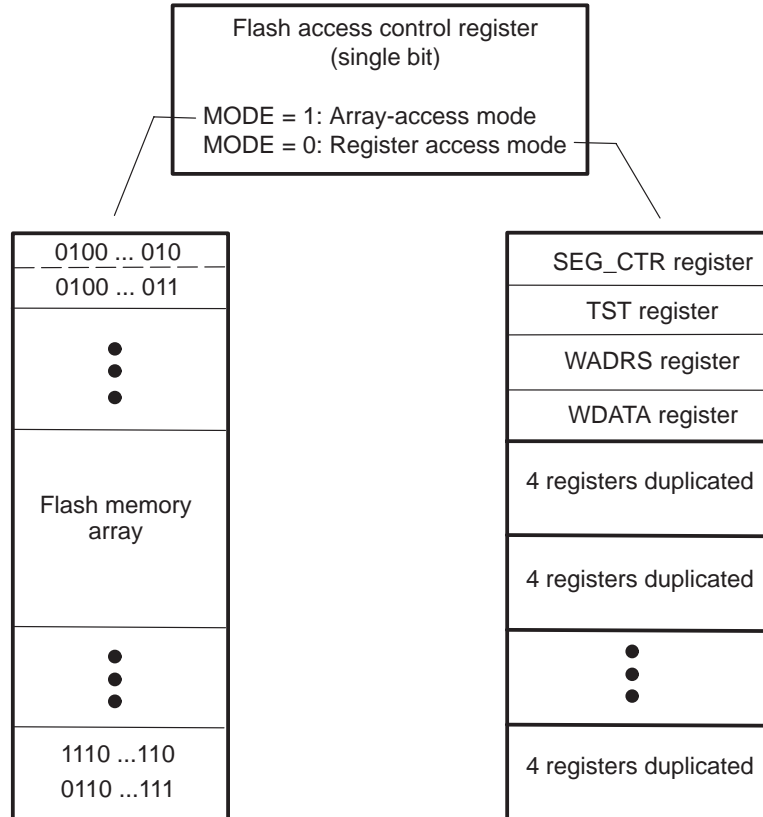
The two access modes are summarized as follows:

- Array-access mode. You can access the flash array in the memory space decoded for the flash module. The flash module remains in this mode most of the time, because it allows the DSP core to read from the memory array.
- Register-access mode. You can access the four control registers in the memory space decoded for the flash module. This mode is used for programming. When the flash module is in register-access mode, the registers are repeated every four address locations within the flash module's address range.

The flash array is not directly accessible as memory in register-access mode, and the control registers are not directly accessible in array-access mode.

Figure 2–2 shows memory maps of the flash array in register and array access modes.

Figure 2–2. Memory Maps in Register and Array Access Modes



2.2.1 TMS320F206 Flash Access-Control Register

Because each flash module has an access-control register associated with it, the 'F206 has two access-control registers. These registers are standard I/O-mapped registers that can be read with an IN instruction and must be modified with an OUT instruction.

- F_ACCESS0 is mapped in I/O space at 0FFE0h.
- F_ACCESS1 is mapped in I/O space at 0FFE1h.

The MODE bit (bit 0) of the access-control register selects the access mode:

- MODE = 0 Register-access mode
- MODE = 1 Array-access mode

Bits 15–1 of each access-control register are always read as 0 and are unaffected by writes.

Although the function is the same, the access control registers of the 'F206 device are mapped at different addresses from that of the 'F24x devices, and their values are modified in a different way.

2.2.2 TMS320F24x Flash Access-Control Register

The access-control register of the 'F24x devices is a special type of I/O-mapped register that cannot be read. The register is mapped at I/O address 0FF0Fh, and it functions as indicated below.

Note:

For both the IN and OUT instructions, the data operand (dummy) is not used, and can be any valid memory location.

An OUT instruction using the register address as an I/O port places the flash module in register-access mode.

For example:

```
OUT    dummy, 0FF0Fh ;Selects register-access mode
```

An IN instruction using the register address as an I/O port places the flash module in array-access mode.

The data operand (dummy) is not used, and can be any valid memory location.

For example:

```
IN     dummy, 0FF0Fh ;Selects array-access mode
```

2.3 Flash Module Control Registers

Table 2–2 lists the control registers and their relative addresses within the four locations that repeat throughout the module’s address range.

Table 2–2. Flash Module Control Registers

Relative Address	Register Name	Description	Described in ...	
			Section	Page
0	SEG_CTR	Segment control register. The eight MSBs enable specific segments for programming. Setting a bit to 1 enables the segment. The eight LSBs control the program, erase, and verify operations of the module.	2.3.1	2-5
1	TST	Test register. Reserved for test; not accessible to the user.	2.3.2	2-8
2	WADRS	Write address register. Holds the address for a write operation.	2.3.3	2-8
3	WDATA	Write data register. Holds the data for a write operation.	2.3.4	2-8

2.3.1 Segment Control Register (SEG_CTR)

SEG_CTR is a 16-bit register that initiates and monitors the programming and erasing of the flash array. This register contains the bits that initiate the active operations (the WRITE/ERASE field and EXE bit), those used for verification (VER0 and VER1), and those used for protection (KEY0, KEY1, and SEG7–SEG0). All bits of SEG_CTR register are cleared to 0 upon reset.

SEG_CTR is shown in Figure 2–3 and the fields are described in Table 2–3.

Figure 2–3. Segment Control Register (SEG_CTR)

15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
SEG7	SEG6	SEG5	SEG4	SEG3	SEG2	SEG1	SEG0	Res	KEY1	KEY0	VER0	VER1	WRITE/ERASE	EXE	
RW-0	RW-0	RW-0	RW-0	RW-0	RW-0	RW-0	RW-0	X	RW-0	RW-0	RW-0	RW-0	RW-0	RW-0	RW-0

Legend: R = read
W = write
-0 = value after reset
X = don't care

Table 2–3. Segment Control Register Field Descriptions

Bits	Name	Description
15–8	SEG7–SEG0	Segment enable bits. Each of these bits protects the specified segment against programming or enables programming for the specified segment in the array. Any number of segments (from 0 to 7 in any combination) can be enabled at any one time. See Table 2–4 for segment address ranges. EXE must be cleared to modify the SEGx bits. SEGx = 1 enables programming of the corresponding segment. SEGx = 0 protects the segment from programming.
7	Reserved	This bit is not affected by writes, and reads of this bit are undefined.
6–5	KEY1, KEY0	Execute key bits. A binary value of 10 must be written to these bits in the same DSP core access in which the EXE bit is set for the selected operation (erase, program, or flash-write) to start. KEY1 and KEY0 must be cleared in the same write access that clears EXE. These bits are used as additional protection against inadvertent programming or erasure of the array. These bits are read as 0s.
4–3	VER0, VER1	Verify bits. These bits select special read modes used to verify proper erasure or programming. Possible values: 00: Normal read mode 01: Verify 1s (VER1) read mode to verify margin of 1s for proper erasure 10: Verify 0s (VER0) read mode to verify margin of 0s for proper programming 11: Inverse-read mode; tests for bits erased into depletion
2–1	WRITE/ERASE	Write/erase enable field. These bits select the program, erase, or flash-write operation. However, modification of the array data does not actually start until the EXE bit is set. Reset clears these bits to zero. Possible values: 00: Read operation is enabled. These bit values are required to read the array. 01: Erase operation is enabled 10: Write operation is enabled 11: Flash-write operation is enabled
0	EXE	Execute bit. In conjunction with WRITE/ERASE, KEY1, and KEY0, this bit controls the program, erase, and flash-write operations. Setting EXE starts and stops programming and erasing of the flash array. The KEY1 and KEY0 bits must be written in the same write access that sets EXE, and EXE must be cleared in the same write access that clears KEY1 and KEY0. EXE must be cleared to modify the SEGx bits.

Note: The segment enable bits are not intended for protection during the erase or flash-write operations. During these operations, *all* segments must be enabled.

Table 2–4. Flash Array Segments Summary

SEG7–SEG0 Bits								'F206/F240 Flash Module†		'F241/F243 Flash Module	Array Segment Enabled
15	14	13	12	11	10	9	8	Flash0	Flash1		
0	0	0	0	0	0	0	1	0000–07FFh	4000–47FFh	0000–03FFh	0
0	0	0	0	0	0	1	0	0800–0FFFh	4800–4FFFh	0400–07FFh	1
0	0	0	0	0	1	0	0	1000–17FFh	5000–57FFh	0800–0BFFh	2
0	0	0	0	1	0	0	0	1800–1FFFh	5800–5FFFh	0C00–0FFFh	3
0	0	0	1	0	0	0	0	2000–27FFh	6000–67FFh	1000–13FFh	4
0	0	1	0	0	0	0	0	2800–2FFFh	6800–6FFFh	1400–17FFh	5
0	1	0	0	0	0	0	0	3000–37FFh	7000–77FFh	1800–1BFFh	6
1	0	0	0	0	0	0	0	3800–3FFFh	7800–7FFFh	1C00–1FFFh	7

† The TMS320F206 has two flash modules. The TMS320F240 device uses the address ranges shown for Flash0.

Although segmentation is not supported during erase (i.e., the entire array must be erased simultaneously), the segment enable bits can be used to protect portions of the array against unintentional programming. This is useful for applications in which different portions of the array are programmed at different times. For example, an application might program the flash module with a large table in $2K \times 16$ blocks. Some time after the first block is programmed, the next block is programmed. The segment enable bits can be used to prevent corruption of the first block while the second block is being programmed.

2.3.2 Flash Test Register (TST)

The flash test register (TST) is a 5-bit register used during manufacturing test of the flash array. This register is not accessible to the DSP core.

2.3.3 Write Address Register (WADRS)

The write address register (WADRS) is a 16-bit register that holds the latched write address for a programming operation. In array-access mode, this register is loaded with the value on the address bus when you are writing a data value to the flash module. It can be loaded directly in register-access mode by writing to it.

2.3.4 Write Data Register (WDATA)

The write data register (WDATA) is a 16-bit register that contains the latched write data for a programming operation. In array-access mode, this register can be loaded by writing a data value to the flash module. It can be loaded directly in register-access mode by writing to it. The WDATA register must be loaded with the value FFFFh before an erase operation starts.

2.4 Read Modes

The 'F20x/F24x flash module uses four read modes and corresponding sets of reference levels:

- Standard
- Verify 0s (VER0)
- Verify 1s (VER1)
- Inverse-erase

Read mode selection is accomplished through the verify bits (bits 3 and 4) in SEG_CTR during execution of the algorithms.

In the standard read mode of the 'F20x/F24x flash module, the supply voltage (V_{DD}) is internally applied to the cell to select it for reading. The VER0, VER1, and inverse-erase read modes differ from the standard read mode in the internal voltage level applied to the flash cell.

Because the program and erase operations must provide sufficient margin on 1s and 0s to ensure data retention, the verify 0s (VER0) and verify 1s (VER1), are provided on the flash module to check for sufficient margin.

The VER0 and VER1 read modes provide a method for adjusting the level on the cells during programming or erasing, beyond the point required for reading a 0 or a 1, creating the required logic level margin. In VER0 mode, a voltage closer to an ideal logic zero level than necessary to read a logic zero is internally applied to the cell to select it for reading. This is the worst-case condition for reading a programmed cell, and if a cell can be read as 0 in VER0 mode, then it can also be read as 0 in standard read mode. Similarly, in the VER1 read mode, a voltage closer to an ideal logic one level than necessary to read a logic one is internally applied to the cell to select it for reading. This is the worst-case condition for reading an erased cell, and if a cell can be read as 1 in the VER1 mode, then it can be read as 1 in standard read mode.

The inverse-erase read mode detects flash bits that are in depletion mode. This read mode applies a voltage to all array cells so that all cells are deselected. The entire array can be tested for bits in depletion mode by reading the first row (32 words) of the array in inverse-erase read mode. If there are no bits in depletion mode, all 32 words are read as 0000h.

2.5 Program Operation

The program operation of the 'F20x/F24x flash module loads the application-specific data (a pattern of 0s) into the flash array. The basis of the operation is applying a program pulse to a single word of flash memory. The term *program pulse* refers to the time during the program operation between the setting and the clearing of the EXE bit (bit 0 of SEG_CTR). During the program pulse, charge is added to the addressed bits via the programming mechanism. Several program pulses may be required to fully program the bits of a word, and the application of program pulses is controlled by the programming algorithm.

The flash location to be programmed is specified by the address in the WADRS register, and the data pattern to be programmed is loaded into the WDATA register. Only the bits that contain a 0 are programmed; any bit positions containing a 1 remain unchanged. (See sections 2.3.3 and 2.3.4 for information about how to load the WADRS and WDATA registers.)

To assure that the 0 bits are programmed with enough margin, the reads associated with programming are performed using the VER0 read mode. After a program pulse has been applied, the byte is read back in VER0 mode to assure that programmed bits can be read as 0 over the entire operating range of the device.

The flash module supports programming of up to eight bits of data. Therefore, although the flash bits are addressed on 16-bit word boundaries, only eight bits can be programmed at a time. The algorithm must limit the programming to eight bits by masking the word to be programmed before writing it to the WDATA register. For example, to mask off the upper byte while programming the lower byte, the data value is logically ORed with 0FF00h in software. When a program pulse is applied, only the selected bits are programmed.

2.6 Erase Operation

The erase operation of the 'F20x/F24x flash module prepares the flash array for programming and enables reprogrammability of the flash array. Before the array can be erased, all bits must be programmed to 0s. This procedure of programming all array locations in preparation for the erase is called *clearing the array*. During the erase, all bits in the array are changed from 0s to 1s. After the erase is finished, a depletion mode test is made to determine whether any bits have been over-erased. If over-erased bits are detected, they must be recovered with the flash-write algorithm, and the clear and erase algorithms must be repeated.

An *erase pulse* is the time during the erase operation between the setting and the clearing of the EXE bit (bit 0 of SEG_CTR). During the erase pulse, the level on all array bits is modified via the erase mechanism.

Erasing the flash array is a block operation. During the erase pulse, all array bits are affected simultaneously. (See Figure 2–1, *Flash Memory Logic Levels During Programming and Erasing*, on page 2-4 for an illustration of this mechanism.) Multiple erase pulses may be required to fully erase all bits in the array, and the application of erase pulses is controlled by the erase algorithm.

The erase operation uses the VER1 read mode to determine when erasure is complete. After erasure is complete, the inverse-erase read mode is used to determine if any bits are over-erased. For more information about these read modes, see section 2.4, *Read Modes*, on page 2-12.

2.7 Recovering From Over-Erase (Flash-Write Operation)

Generally, not all bits in the flash array have the same amount of charge removed with each erase pulse. By the time all bits have reached the VER1 read margin (and erase is complete), some of the bits in the array may be over-erased. They are said to be in depletion mode. If even one single flash cell is over-erased into depletion mode, it is always read as logic 1 and can corrupt the reading of other bits. This condition must be detected and corrected, because it also inhibits reprogramming of the flash array.

The 'F20x/F24x flash array employs the flash-write operation to recover bits that are erased into depletion mode. The flash-write operation is similar to the erase operation in that it affects all bits in the array simultaneously. This enables recovery of multiple bits from depletion mode, but requires the flash-write operation to be followed by the clear and erase operations to restore the erase margin on all bits.

A *flash-write pulse* is the time during the flash-write operation between the setting and the clearing of the EXE bit (bit 0 of SEG_CTR). During the flash-write pulse, all array bits are affected simultaneously. (See Figure 2-1, *Flash Memory Logic Levels During Programming and Erasing*, on page 2-4 for an illustration of this mechanism.) Multiple flash-write pulses may be required to fully recover all bits in the array, and the application of flash-write pulses is controlled by the flash-write algorithm.

The flash-write operation uses the inverse-erase read mode and inverse-erase reference level to detect bits that are in depletion mode. For more information about the inverse-erase read mode, see section 2.4, *Read Modes*, on page 2-12.

2.8 Reading From the Flash Array

Once the array is programmed, it is read in the same manner as other memory devices on the DSP memory interface. The flash module operates with zero wait states. When you are reading the flash module, the flash segment control register (SEG_CTR) bits should be 0 and the flash array must be in the array-access mode.

2.9 Protecting the Array

After the flash memory array is programmed, it is desirable to protect the array against corruption. The flash module of the 'F20x/F24x DSPs includes several protection mechanisms to prevent unintentional modification of the array.

Flash programming is facilitated via the supply voltage connected to the VCCP pin. If this pin is grounded, the program operation will not modify the flash array. Note, that grounding the VCCP pin does not prevent the erase operation; other protection mechanisms for the erase operation are discussed below.

The control registers provide the following mechanisms for protecting the flash array from unintentional modification.

- Segment enable bits
- EXE, KEY0, and KEY1 bits
- WDATA register

An array segment is prevented from being programmed when the corresponding segment enable bit in the SEG_CTR is cleared to zero. Additionally, all segment enable bits are cleared by reset, making unintentional programming less likely. Even if the segment enable bits are set to one, the program, erase, and flash-write operations are not initiated unless the appropriate values are set in the EXE, KEY0, and KEY1 bits of the SEG_CTR.

At the start of an operation, the KEY1 and KEY0 bits must be written in the same write access that sets EXE. When the program pulse, erase pulse, or flash-write pulse is finished, EXE must be cleared in the same write that clears KEY1 and KEY0. The data and address latches are locked whenever the EXE bit is set, and all attempts to read from or write to the array are ignored (read data is indeterminate). Once the EXE bit is set, all register bits are latched and protected. You must clear EXE to modify the SEGx bits. This protects the array from inadvertent change. Unprotected segments cannot be masked in the same register load with the deactivation of EXE. Additional security is provided by a function of the WDATA register to prevent unintentional erasure. The WDATA register must be loaded with FFFFh before the erase operation is initiated. If the register is not loaded with this value, the array will not be modified.

Algorithm Implementations and Software Considerations

This chapter discusses the implementations of the algorithms for performing the operations described in the previous chapter. It also discusses items you must consider when incorporating the algorithms into your 'F20x/F24x DSP application code.

Topic	Page
3.1 How the Algorithms Fit Into the Program-Erase-Reprogram Flow	3-2
3.2 Programming (or Clear) Algorithm	3-4
3.3 Erase Algorithm	3-10
3.4 Flash-Write Algorithm	3-14

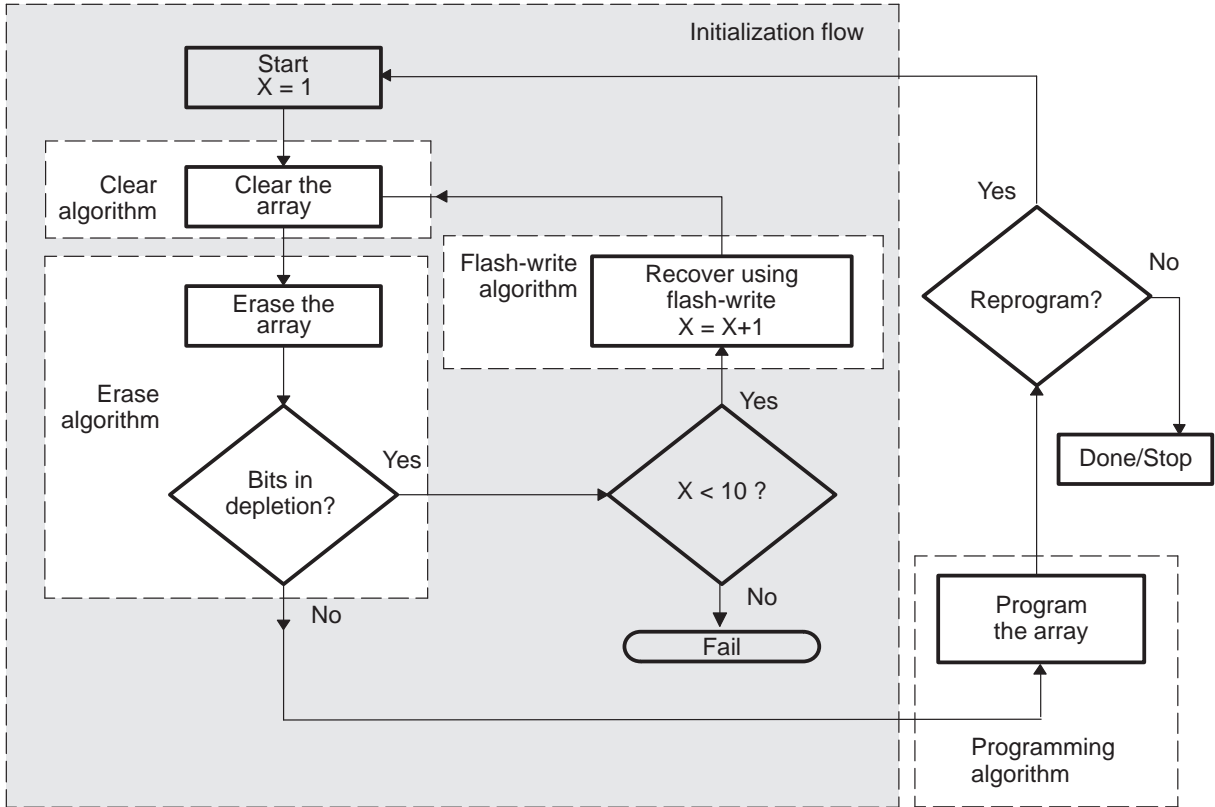
3.1 How the Algorithms Fit Into the Program-Erase-Reprogram Flow

The algorithms discussed in this chapter can be used to reprogram the 'F20x/F24x flash module multiple times. The clear algorithm, erase algorithm, and flash-write algorithm are used to prepare the flash memory for programming, while the programming algorithm is used to write a desired pattern of 0s to the array (program the array).

The programming algorithm and the clear algorithm are both implementations of the program operation. The difference between the two is the data that is written: the programming algorithm programs the user data, while the clear algorithm uses all 0s. All of the algorithms can be viewed as portions of a single flow diagram, as shown in Figure 3–1.

Note that in the algorithm flowcharts, the variable X represents the number of attempts at depletion recovery using the flash-write algorithm. It has been shown that if flash-write is not successful in depletion recovery after ten attempts, depletion recovery is not possible, and a device failure has occurred. Therefore, if ten flash-write attempts at depletion recovery are not successful, the algorithm returns a device failure error message.

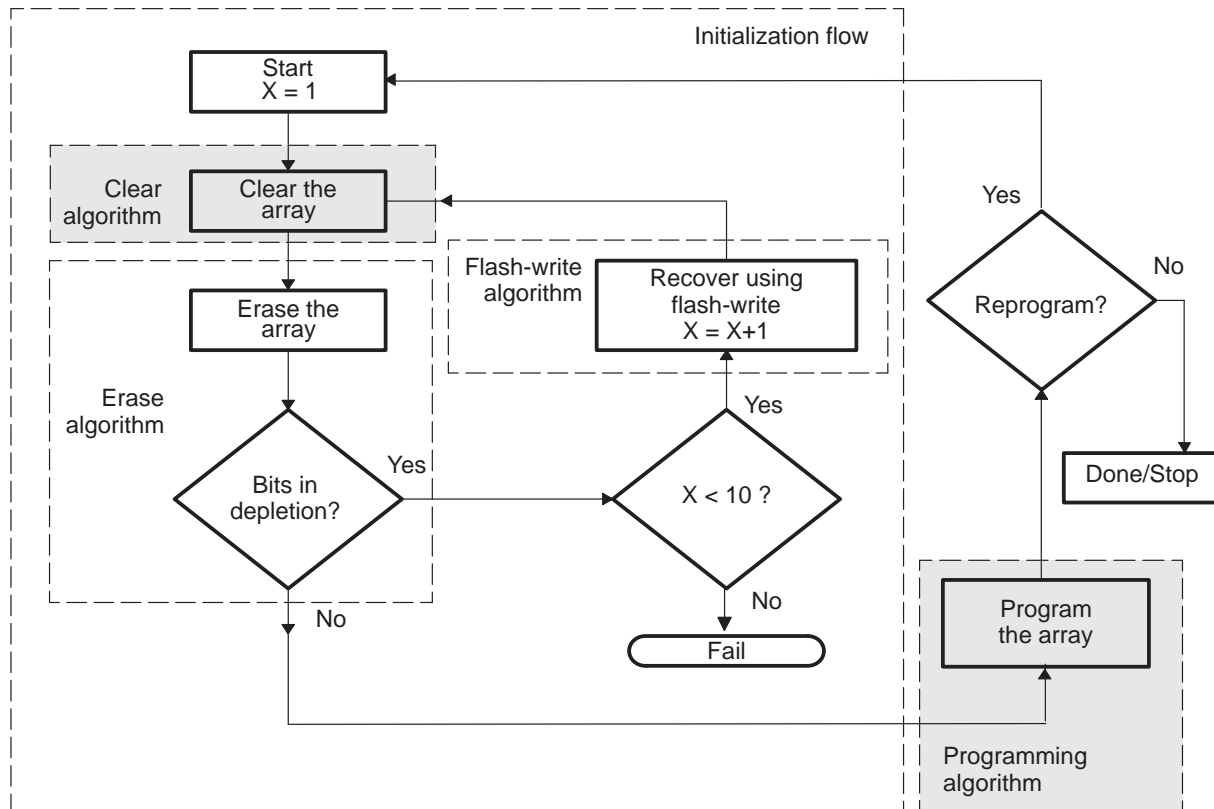
Figure 3-1. Algorithms in the Overall Flow



3.2 Programming (or Clear) Algorithm

The programming algorithm sequentially writes any number of addresses with a specified bit pattern. This algorithm is used to program application code or data into the flash array. With a slight modification, the same algorithm performs the clear portion of the initialization flow (i.e., programs all bits to zero). In this role, the algorithm is called the clear algorithm. For the clear algorithm, the values programmed are always 0000h, while the values for application code can be any combination of 1s and 0s. Figure 3–2 highlights the programming and clear algorithms' place in the overall flow.

Figure 3–2. The Programming Algorithm in the Overall Flow



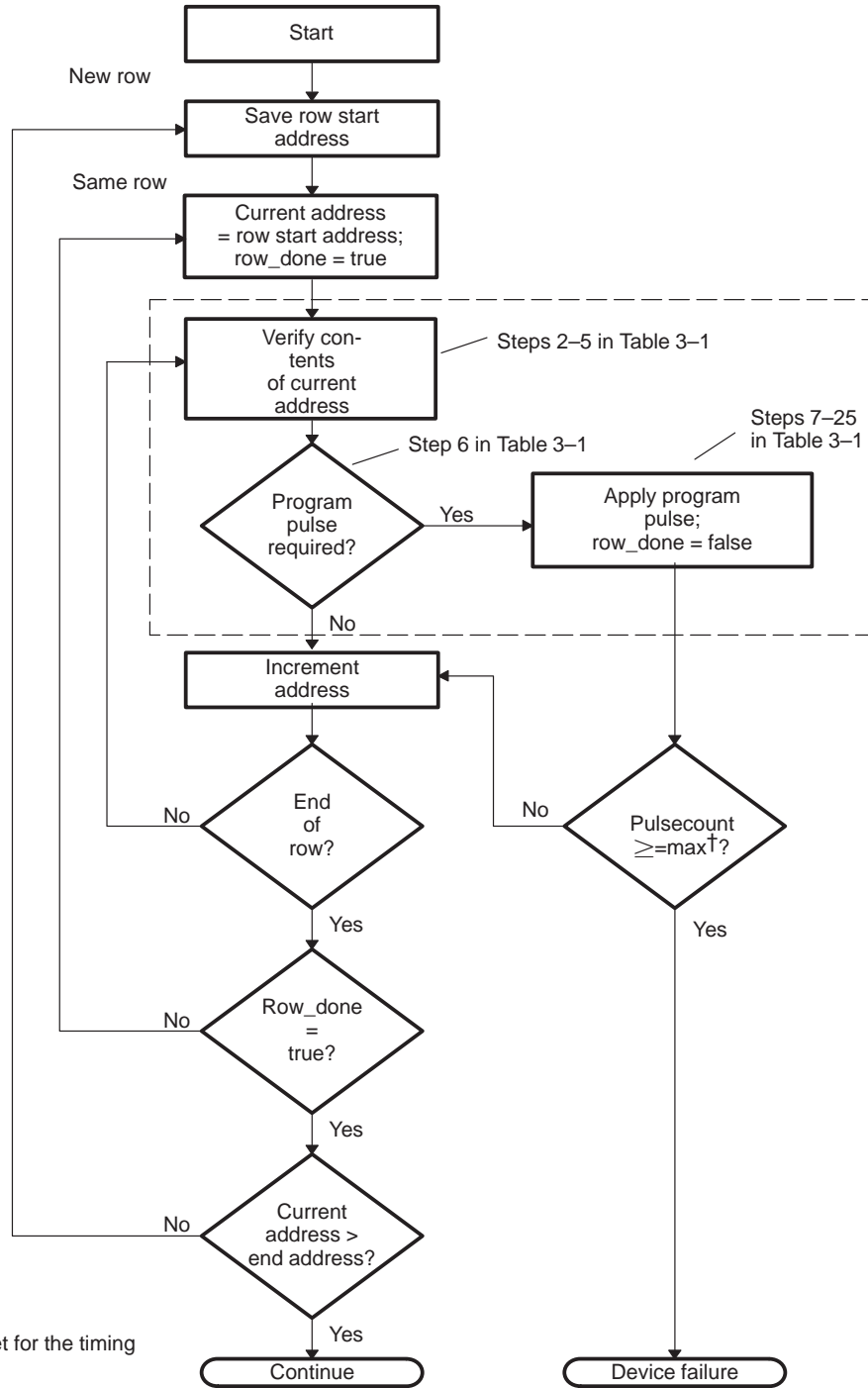
The main feature of the program/clear algorithm is the concept of programming an entire row of bits in a group. The 'F20x/F24x flash array is organized in rows of 32 words. That is, addresses 0000h through 001Fh are physically located on the same row of the flash memory array. The array is designed so that there is a dependence between the charge levels on adjacent (even-odd) addresses during programming. Programming the bits of an odd address reduces the charge margin of the programmed bits (the 0s) in the preceding adjacent (even) address within the row. Similarly, programming the bits of an even address reduces the charge margin of the programmed bits in the next adjacent (odd) address within the row. Because of this dependence, if each address is programmed individually, the charge levels among programmed bits is not uniform. The programming algorithm improves the uniformity of charge levels on programmed bits by programming all of the words of a row in a group. For example, the contents of address 0000h is compared with the data to be programmed and one program pulse is applied if necessary. The same procedure is performed on addresses 0001h through 001Fh. The procedure repeats starting at address 0000h until no more program pulses are required for any address in the row. The number of iterations of this loop equals the maximum number of program pulses required to program the bits in the row.

The flow for the programming algorithm is shown in Figure 3-3, and the assembly code is given in Appendix A.

An important consideration for programming the flash array is the CPU frequency range for the application. Because of the actual implementation of the flash memory circuitry, a 0 bit is most easily read at high frequency; programmed bits have less margin when read at lower frequency. So, if the application requires a variable CPU clock rate, programming should be performed at the lowest frequency in the range. (A similar condition exists for the erase operation, which requires execution of the erase algorithm at the highest frequency in the range. See section 3.3, page 3-10.)

Only the read portion of the program operation must be performed at the lower frequency, because the read is used to determine margin. The read operation can be extended by sequentially executing multiple reads on the same location. Because the same address is selected the entire time and internal control signals are maintained between reads, the final read is equivalent to a slow read. For example, if the DSP core is executing the programming algorithm at a CLKOUT rate of 20 MHz (50 ns), sequentially reading a location three times is equivalent to reading it once at 6.67 MHz (150 ns). This is important, because it facilitates execution of the program and erase algorithms at the same CLKOUT rate.

Figure 3–3. Programming or Clear Algorithm Flow



† See the device data sheet for the timing parameter values.

Another important consideration is the total amount of time required to do the programming. The number of programming pulses required to completely program a flash memory cell increases as ambient temperature increases and/or supply voltage decreases. More programming pulses are required when the minimum supply voltage is used than when the nominal or maximum supply voltage is used. The number of program pulses required also increases throughout the life of the device, as more program-erase cycles are carried out. The device data sheet specifies the maximum number of program pulses under all operating conditions; use this number when you calculate the maximum amount of time required for programming.

The algorithm incorporates the steps for applying a program pulse (outlined in Table 3–1) along with some other techniques to ensure margin. In general, not all flash bits require the same number of program pulses to reach the programmed margin level. For this reason, the programming algorithm applies a series of short program pulses until the memory location is programmed. However, to understand how the series of program pulses works, you must first understand how the algorithm applies a single program pulse. Table 3–1 outlines the steps involved in verifying programmed bits and applying a single pulse to each of the upper and lower bytes of a single location. This process corresponds to the steps enclosed in the dashed box in the flowchart in Figure 3–3.

Table 3–1. Steps for Verifying Programmed Bits and Applying One Program or Clear Pulse

Step	Action	Description
1	Power up the V _{CCP} pin.	Set the V _{CCP} pin to V _{DD} . If the V _{CCP} pin for the flash module to be programmed is not set to V _{DD} , then the array will not be programmed.
2	Activate VER0 mode.	Set the VER0 bit in SEG_CTR (load SEG_CTR with 0010h).
3	Delay for VER0 reference voltage stabilization.	The CPU executes a delay loop for the t _{d(VERIFY-SETUP)} [†] time period.
4	Read flash array contents for verification.	The CPU reads the addressed location. The flash module must be in array-access mode (see section 2.2, <i>Accessing the Flash Module</i> , page 2-5).
5	Deactivate VER0 mode.	Clear the VER0 bit in SEG_CTR (load SEG_CTR with 0000h).
6	Compare contents of flash location (16 bits) with desired data.	If the verification passes (i.e., if the data read in step 4 is equal to the desired data value), then no further program pulses are required. The flash word has been programmed with the desired data value. The program or clear function is completed and this algorithm is exited. If the verification fails (i.e., if the data read in step 4 is not equal to the desired data value), then proceed to step 7.

Table 3–1. Steps for Verifying Programmed Bits and Applying One Program or Clear Pulse (Continued)

Step	Action	Description
7	Mask the data to program lower byte.	Mask any bits in the lower byte that do not require programming (are already read as zero), and mask off upper byte. Recall that the algorithm should mask one byte while programming the other because a maximum of eight bits can be programmed simultaneously.
8	Load WADRS and WDATA registers.	If the flash module is in array access mode, write the data to be programmed to its address. If the flash module is in register access mode, load the individual registers directly.
10	Activate the WRITE/ERASE field and enable segments.	Set the WRITE/ERASE field in SEG_CTR to 10 and set the corresponding segment enable bits (SEG0–SEG7) for the segments where the programmed word resides.
† See the device data sheet for the timing parameter values.		
11	Wait for internally generated supply voltage stabilization time.	The CPU executes a delay loop for the $t_{d(PGM-MODE)}^{\dagger}$ time period.
12	Initiate the program pulse.	Load the EXE, KEY1, and KEY0 bits with 1, 1, and 0, respectively. All three bits must be loaded in the same write cycle. The segment enable bits and the WRITE/ERASE field must also be maintained.
13	Delay for program pulse time.	The CPU executes a delay loop for the $t_{d(PGM)}^{\dagger}$ time period.
14	Terminate the program pulse.	Clear the WRITE/ERASE field and EXE bit in SEG_CTR (e.g., load SEG_CTR with 0000h).
15	Delay for array stabilization time.	The CPU executes a delay loop for the $t_{d(BUSY)}^{\dagger}$ time period.
16–25	Program upper byte if necessary.	Repeat steps 7–15 for the upper byte. Mask the lower byte to 1s when programming the upper byte.

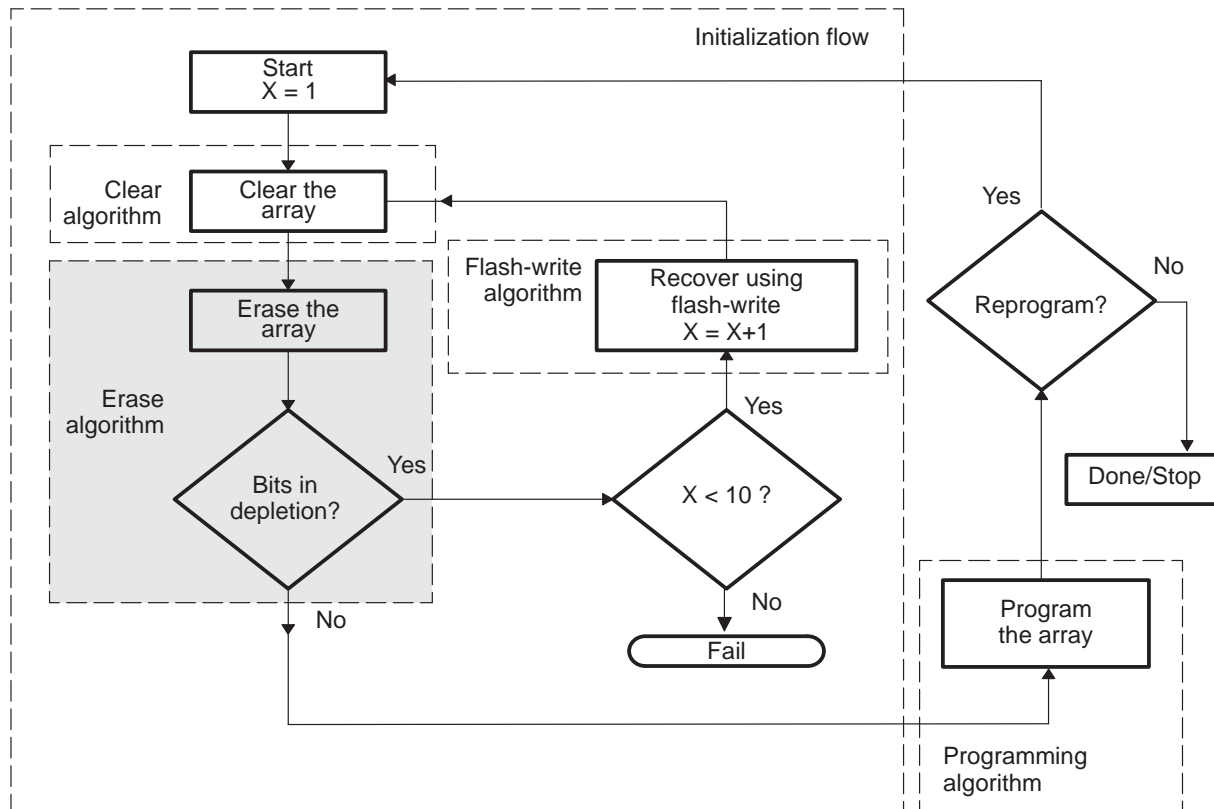
† See the device data sheet for the timing parameter values.

Before each program pulse is applied, a read of the byte is performed to determine which bits have reached the programmed level. Any bits that have reached the programmed level are masked (set to 1 in the WDATA register). This method of programming provides uniform charge levels among programmed bits, whereas using a single, long program pulse could result in some bits having much more charge than others. The uniformity of charge levels among bits has the primary effect of reducing programming time and the secondary effect of reducing the time for a subsequent erase operation. To assure that the bits are programmed with enough margin, the reads associated with programming use the VERO read mode.

3.3 Erase Algorithm

The erase algorithm follows the clear algorithm in executing the entire initialization flow. Figure 3–4 highlights the erase algorithm's place in the overall flow.

Figure 3–4. Erase Algorithm in the Overall Flow



The erase algorithm consists of multiple iterations of a loop with one erase pulse applied in each iteration. Table 3–2 outlines the steps involved in applying a single erase pulse.

Table 3–2. Steps for Applying One Erase Pulse

Step	Action	Description
1	Power up the V _{CCP} pin.	Set V _{CCP} pin to V _{DD} . If the V _{CCP} pin for the flash module to be erased is not set to V _{DD} , then the array will not be erased properly.
2	Load WDATA register with FFFFh.	This load overrides the erase protection mechanism.
3	Activate the erase mode and enable segments.	Set the WRITE/ERASE field to 01 and set SEG0–SEG7 bits in the SEG_CTR register. The flash module must be in register-access mode (see section 2.2).
4	Wait for internally generated supply voltage stabilization time.	The CPU executes a delay loop for the $t_{d(ERASE-MODE)}^{\dagger}$ time period.
5	Initiate the erase pulse.	Load the EXE, KEY1, and KEY0 bits with 1, 1, and 0, respectively. All three bits must be loaded in the same write cycle. The segment enable bits and the WRITE/ERASE field must also be maintained.
6	Delay for erase pulse time.	The CPU executes a delay loop for the $t_{d(ERASE)}^{\dagger}$ time period.
7	Terminate the erase pulse.	Clear the EXE bit and WRITE/ERASE field in the SEG_CTR register (load SEG_CTR with 0000h to clear all bits).
8	Delay for mode deselect time.	CPU executes a delay loop for the $t_{d(BUSY)}^{\dagger}$ time period.

[†] See the device data sheet for the timing parameter values.

At the beginning of each iteration, a read operation is performed on all the bits in the array to determine if an erase pulse is required. Erasure is complete when all array locations are read as FFFFh. To assure that the flash array is erased with enough margin, the reads associated with the erase use the VER1 read mode. Additional margin can be gained during the erase operation if the reads are performed using *address complementing*. When the array is read with address complementing, the following sequence is used for each address read:

- 1) All of the bits of the address to be read are complemented.
- 2) The contents of the resulting address are read.
- 3) The value read at the complemented address is discarded.

- 4) The actual address is restored.
- 5) The contents of the restored address are read.

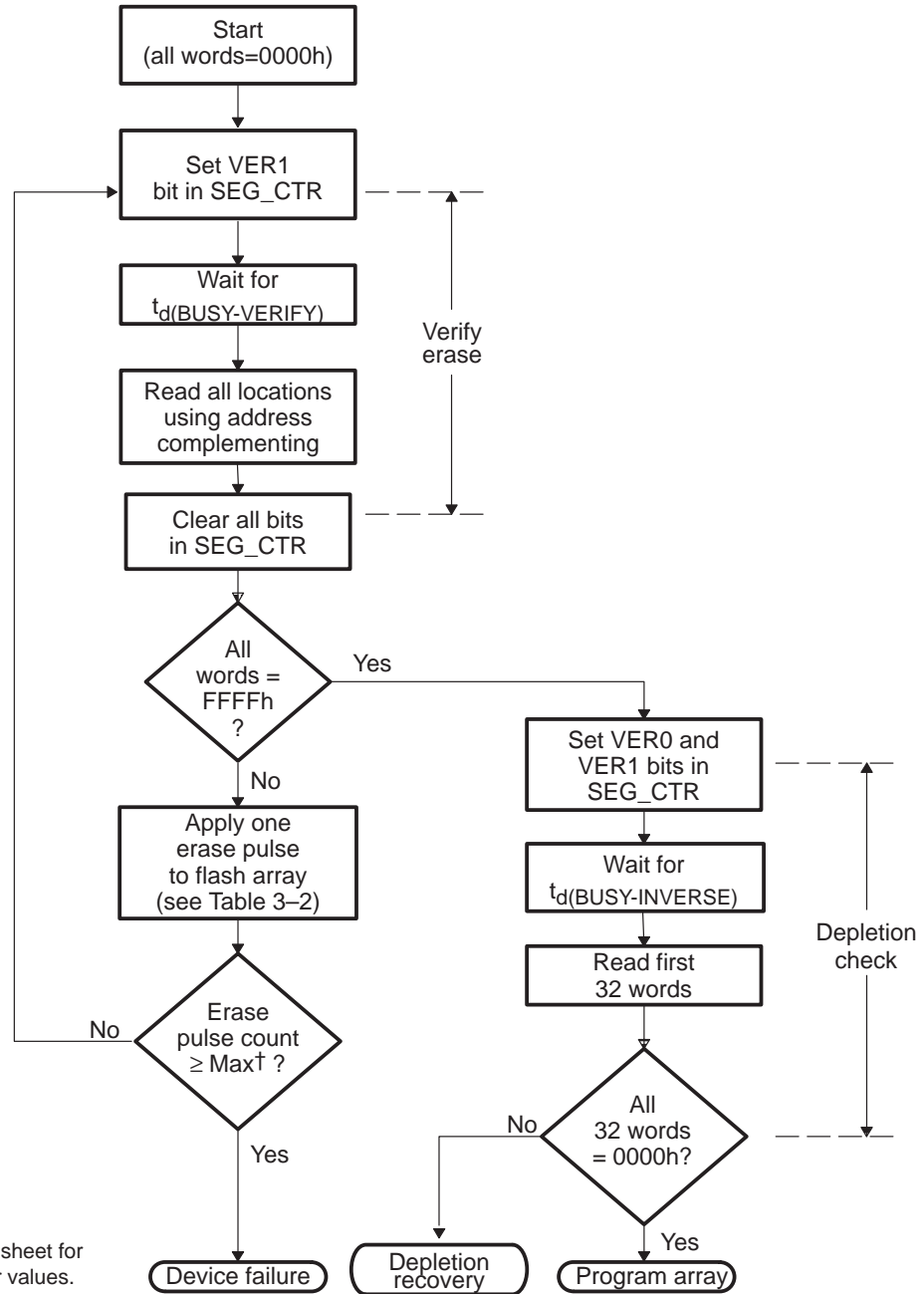
The advantage of this approach is that it forces the worst-case switching condition on the flash addressing logic during the reads, thus improving the margin of the erase. Address complementing on the 'F20x/F24x can be accomplished easily by using the XOR instruction to complement the bits of the address.

An important consideration for erasing the flash array is the CPU frequency range for the application. Because of the actual implementation of the flash memory circuitry, a logic 1 is most easily read at low frequency; erased bits have less margin when read at higher frequency. Accordingly, if the application requires a variable CPU clock rate, the erase should be performed at the highest frequency in the range. (A similar condition exists for the programming operation, which requires execution of the programming algorithm at the lowest frequency in the range. See section 3.2, page 3-4.)

Another important consideration is the total amount of time required to erase the array. The number of erase pulses required to completely erase a flash memory cell increases as ambient temperature increases or decreases relative to the nominal temperature and as supply voltage decreases. More erase pulses are required when the ambient temperature is toward the extremes of the operating range. Also, more erase pulses are required when the minimum supply voltage is used than when the nominal or maximum supply voltage is used. The number of erase pulses required also increases throughout the life of the device, as more program-erase cycles are carried out. The device data sheet specifies the maximum number of erase pulses under all operating conditions; use this number when you calculate the maximum amount of time required for the erase algorithm.

The complete erase algorithm including depletion check is shown in the flow-chart in Figure 3-5.

Figure 3–5. Erase Algorithm Flow

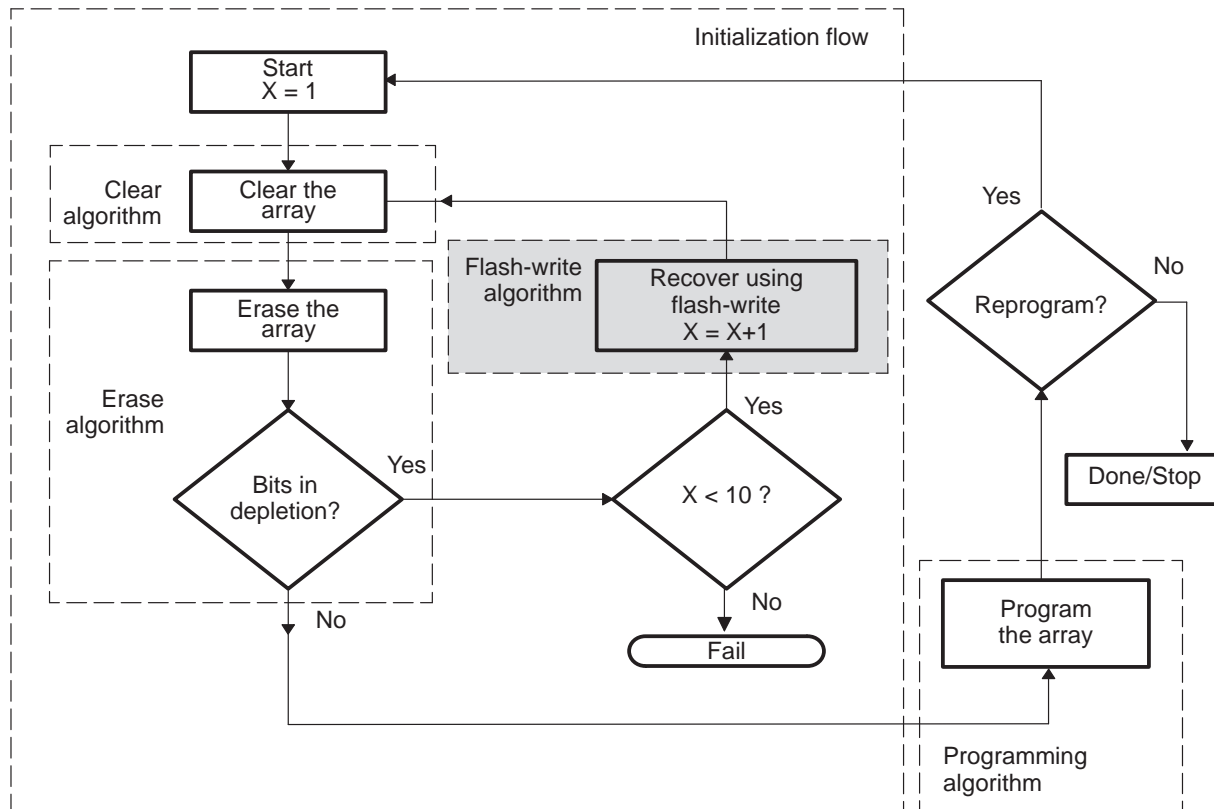


† See the device data sheet for the timing parameter values.

3.4 Flash-Write Algorithm

The flash-write operation recovers bits in depletion mode, which can be caused by over-erasure. The flash-write algorithm's place in the overall flow is highlighted in Figure 3–6.

Figure 3–6. Flash-Write Algorithm in the Overall Flow



A *flash-write pulse* is the time during the flash-write operation between the setting and the clearing of the EXE bit (bit 0 of SEG_CTR). Charge is added to the bits of the flash memory array via the flash-write mechanism. The flash-write algorithm may require multiple flash-write pulses. The steps required to apply one flash-write pulse are outlined in Table 3–3.

Table 3–3. Steps for Applying One Flash-Write Pulse

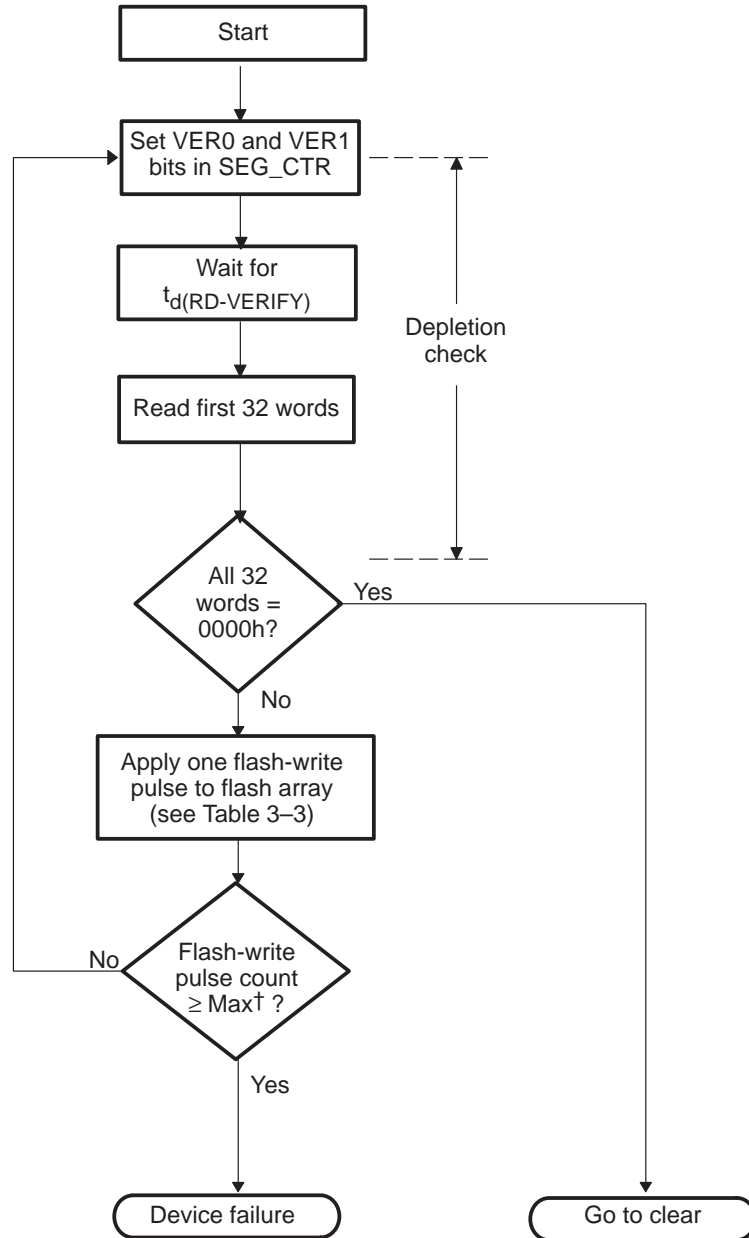
Steps	Action	Description
1	Power up the V_{CCP} pin.	Set the V_{CCP} pin to V_{DD} . If the V_{CCP} pin for the flash module to be recovered is not set to V_{DD} , then the flash-write operation will not be effective.
2	Activate the flash-write mode and enable all segments.	Set the WRITE/ERASE field to 10 and set SEG0–SEG7 in the SEG_CTR register. The flash module must be in register access mode (see section 2.2).
3	Wait for the internally generated supply voltage stabilization time.	The CPU executes a delay loop for the $t_{d(FLW-MODE)}^{\dagger}$ time period.
4	Initiate the flash-write pulse.	Load the EXE, KEY1, and KEY0 bits with 1, 1, and 0, respectively. All three bits must be loaded in the same write cycle. The segment enable bits and WRITE/ERASE field must also be maintained.
5	Delay for the flash-write pulse time.	The CPU executes a delay loop for the $t_{d(FLW)}^{\dagger}$ time period.
6	Terminate the flash-write pulse.	Clear all bits in the SEG_CTR register (load SEG_CTR with 0000h).
7	Delay for mode deselect time.	CPU executes a delay loop for the $t_{d(BUSY)}^{\dagger}$ time period.

[†] See the device data sheet for the timing parameter values.

The flash-write algorithm consists of multiple iterations of a loop with one flash-write pulse applied in each iteration. At the beginning of each iteration, a depletion test is performed to determine if a flash-write pulse is required. Figure 3–7 shows the flow of the flash-write algorithm.

The flash-write operation uses the inverse-erase read mode to detect bits that are in depletion mode. For more information about the inverse-erase read mode, see section 2.4, *Read Modes*, on page 2-12.

Figure 3–7. Flash-Write Algorithm Flow



The CPU frequency range for the application is an important consideration for the depletion test, as well as for the program and erase operations. Because of the actual implementation of the flash memory circuitry, a bit in depletion mode is most easily detected at low frequency. Accordingly, if the application requires a variable CPU clock rate, the depletion test should be performed at the lowest frequency in the range. Only the read portion of the depletion test must be performed at the lower frequency, because it is the read that is used to detect depletion. The effective duration of the read operation can be extended by sequentially executing multiple reads on the same location. Because the same address is selected the entire time and internal control signals are maintained between reads, the final read is equivalent to a slow read. For example, if the DSP core is executing the programming algorithm at a CLKOUT rate of 20 MHz (50 ns), sequentially reading a location three times is equivalent to reading it once at 6.67 MHz (150 ns). The erase and flash-write algorithm implementations given in Appendix A use three reads to check for depletion.

PRELIMINARY

PRELIMINARY

Assembly Source Listings and Program Examples

The flash array is erased and programmed by code running on the DSP core. This code can originate from off-chip memory or can be loaded into on-chip RAM. The available flash programming tools for the 'F20x/F24x allow you to program the on-chip flash module without having knowledge or visibility of the algorithms. One scheme uses the scan emulation feature of the 'F20x/F24x to load the algorithms onto the DSP and control execution, and another scheme relies on boot loader code preprogrammed into the flash memory at the factory. You can find more information about these stand-alone flash programming tools on the Texas Instruments web page at <http://www.ti.com>. This appendix explains how to use the algorithm source files to program the flash module. You need this information to create new flash programming tools or to add such features as remote reprogrammability to a design.

Topic	Page
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A.2 C-Callable Interface to Flash Algorithms	A-27
A.3 Sample Assembly Code to Erase and Reprogram the TMS320F206	A-32
A.4 Sample C Code to Erase and Reprogram the TMS320F206	A-37
A.5 Sample Assembly Code to Erase and Reprogram the TMS320F240	A-40
A.6 Using the Algorithms with C Code to Erase and Reprogram the TMS320F240	A-47

A.1 Assembly Source for Algorithms

The algorithm source files implement the flows given in Chapter 3. Each algorithm is written as an assembly language subroutine, beginning with a label at an entry point and ending with a return instruction. The algorithms share a set of 16 relocatable variables for which pointers are defined in the header file, SVAR20.H.

The variables are defined at the beginning of B1 RAM, and an uninitialized section should be declared at link time to reserve this space. Also, the data page pointer (DP) should be initialized to point to this space before a call is made to any of the algorithms.

In addition to these variables, each algorithm references parameters that should be declared globally in the calling code. These parameters are listed in the introduction to each of the algorithm source files below.

The source files given are:

- SVAR20.H: header file that defines variables and constants
- SCLR20.ASM: clear algorithm
- SERA20.ASM: erase algorithm
- SFLW20.ASM: flash-write algorithm
- SPGM20.ASM: programming algorithm
- SUTILS20.ASM: subroutines common to all four algorithms

The same algorithm files can be used for the TMS320F206 and the TMS320F240/1/3 devices. A conditional assembly variable is provided in the header file, SVAR20.H, for assembling the algorithms for the correct device. For more details on this conditional assembly variable, see A.1.1.

A.1.1 Header File for Constants and Variables, SVAR20.H

This header file is included in each of the algorithm files using the `.include` directive. All of the constants used for flash programming are defined in this file. Also, the conditional assembly constant, `F24x`, is defined here to allow reuse of the algorithms for multiple device types. This constant should be modified to select the correct device when the algorithms are assembled. The SVAR20.H header file can also be included in the calling code, to allow visibility to the variable names.

```

*****
** Variable declaration file **
* **
* TMS320F2XX Flash Utilities. **
* Revision: 2.0, 9/10/97 **
* Revision: 2.1, 1/31/98 **
* **
* Filename: svar20.asm **
* **
*Note: **
*DLOOP is a delay loop variable used in flash algorithms. **
*This is a function of CLKOUT1. If the F206 device runs at **
*any CLKOUT1 speed other than 20 MHz, DLOOP value should be **
*redefined per the equation explained below. Use of **
*current DLOOP for flash programming at speeds other than **
*20 MHz is not recommended. **
*****
        .mmregs
BASE    .set    0300h           ;Base address for variables
                                           ;can be changed to relocate
                                           ;variable space in RAM.
BASE_0  .set    BASE+0        ;Scratch pad registers.
BASE_1  .set    BASE+1        ;
BASE_2  .set    BASE+2        ;
BASE_3  .set    BASE+3        ;
BASE_4  .set    BASE+4        ;
BASE_5  .set    BASE+5        ;
BASE_6  .set    BASE+6        ;
SPAD1   .set    BASE+7        ;
SPAD2   .set    BASE+8        ;
FL_ADRS .set    BASE+10       ;Flash load address.
FL_DATA .set    BASE+11       ;Flash load data.
ERROR   .set    BASE+15       ;Error flag register.
*Variables for ERASE and CLEAR
RPG_CNT .set    BASE+12       ;Program pulse count.
FL_ST   .set    BASE+13       ;Flash start addr/Seg Cntrl Reg.
FL_END  .set    BASE+14       ;Flash end address.
*

```

```

*CONSTANTS
*
*****
*Conditional assembly variable for F24X vs F206.      *
*If F24X = 1, then assemble for F24X; otherwise,      *
*assemble for F206.                                  *
*****
F24X      .set      0          ;Assemble for F206
;F24X     .set      1          ;Assemble for F24X
*****
* Delay variables for CLEAR,ERASE and PROGRAM *
*****
D5        .set      0          ;5 us delay
D10       .set      1          ;10 us delay
D100      .set      19         ;100 us delay
D5K       .set      999        ;5 ms delay
D7K       .set      1399       ;7 ms delay
*****
*DLOOP constant proportional to CLKOUT1              *
*Calculate DLOOP in decimal using the following equation: *
* DLOOP=FLOOR{(5us/tCLKOUT1)-6};                    *
*Examples                                           *
*a.@ 15 MHz, DLOOP= 69;                             *
*b.@ 9.8304 MHz, DLOOP= 43;                          *
*c.@ 16.384 MHz, DLOOP= 75;                          *
*****
;DLOOP    .set      14         ;5-us delay loop @ 4.032 MIPS
;DLOOP    .set      19         ;5-us delay loop @ 5 MIPS
;DLOOP    .set      44         ;5-us delay loop @ 10 MIPS
;DLOOP    .set      75         ;5-us delay loop @ 16.384 MIPS
;DLOOP    .set      94         ;5-us delay loop @ 20 MIPS
*****
* On-chip I/O registers *
*****
F_ACCESS0 .set      0FFE0h ;F206 ACCESS CNTRL REGISTER 0.
F_ACCESS1 .set      0FFE1h ;F206 ACCESS CNTRL REGISTER 1.
PMST      .set      0FFE4h ;Defines SARAM in PM/DM and MP/MC bit.
F24X_ACCS .set      0FF0Fh ;F240 ACCESS CNTRL REGISTER.
;-----
;Register Declarations for F240 Peripherals |
;-----
;Watch-Dog(WD)/Real Time Int(RTI)/Phase-Locked Loop (PLL)
;Registers
;~~~~~
RTI_CNTR  .set      07021h     ;RTI Counter reg
WD_CNTR   .set      07023h     ;WD Counter reg
WD_KEY    .set      07025h     ;WD Key reg
RTI_CNTL  .set      07027h     ;RTI Control reg
WD_CNTL   .set      07029h     ;WD Control reg
PLL_CNTL1 .set      0702Bh     ;PLL control reg 1
PLL_CNTL2 .set      0702Dh     ;PLL control reg 2

```


A.1.2 Clear Algorithm, SCLR20.ASM

This code is an implementation of the clear (programming) algorithm described in section 3.2 on page 3-4. Recall that the clear algorithm is identical to the programming algorithm with the data forced to 0000h for all flash addresses.

Memory section: **fl_clr**

Entry point: **GCLR**

Parameters to be declared and initialized by the calling code are:

- PROTECT defines the values of bits 8–15 of SEG_CTR during the clear algorithm.
- SEG_ST defines the start address of the flash array to be cleared.
- SEG_END defines the end address of the flash array to be cleared.

Return value: **ERROR** (@BASE+15); 0 = Pass, 1 = Fail

```
*****
** CLEAR Subroutine                                     **
*                                                       **
* TMS320F2XX Flash Utilities.                           **
*   Revision: 2.0, 9/10/97                               **
*   Revision: 2.1, 1/31/98                               **
*                                                       **
* Filename: sclr20.asm                                   **
*                                                       **
* Called by: c2xx_bcx.asm or flash application programs. **
*                                                       **
* !!CAUTION - INITIALIZE DP BEFORE CALLING THIS ROUTINE!! **
*                                                       **
* Function: Clears one or more contiguous segments of   **
* array 0/1 as specified by the following               **
* variables.                                           **
*   SEG_ST      Segment start address                   **
*   SEG_END     Segment end address                     **
*   PROTECT     Sector protect enable                   **
*                                                       **
* The algorithm used is "row-horizontal", which means that *
* an entire flash row (32 words) is programmed in parallel.*
* This method provides better uniformity of programming  *
* levels between adjacent bits than if each address were *
* programmed independently. The algorithm also uses a    *
* 3-read check for VERO margin (i.e., the flash location is *
* read three times and the first two values are discarded.)*
* This provides low-frequency read-back margin on        *
```

```

*   programmed bits. For example, if the flash is programmed *
*   using a CLKOUT period of 50 ns, the flash can be read back *
*   reliably over the CLKOUT period range of 50 ns to 150 ns *
*   (6.67 MHz-20 MHz). The programming pulse-duration is      *
*   100 us, and a maximum of 150 pulses is applied per row.  *
*
*   The following resources are used for temporary storage:
*       AR0      Used for comparisons
*       AR1      Used for pgm pulse count
*       AR2      Used for row banz loop.
*       AR6      Parameter passed to Delay
*       FL_ADRS  Used for flash address
*       FL_DATA  Used for flash data.
*       FL_ST    Used for flash start address
*       BASE_0   Used for row-done flag
*       BASE_1   Used for row start address
*       SPAD1    Flash commands
*       SPAD2    Flash commands
*
*****
                .include "svar20.h"
*
MAX_PGM  .set      150      ;Only allow 150 pulses per row.
VER0     .set      010h     ;VER0 command.
WR_CMND  .set      4        ;Write command.
WR_EXE   .set      045h     ;Write EXEBIN command.
STOP     .set      0        ;Reset command.
        .def      GCLR
        .ref      PROTECT,SEG_ST,SEG_END
        .ref      DELAY,REGS,ARRAY
        .sect     "fl_clr"
*****
*   GCLR: This routine performs a clear operation on the *
*   flash array defined by the FL_ST variable. The segments *
*   to be cleared are defined by the SEG_ST, SEG_END, and *
*   PROTECT variables.
*   The following resources are used for temp storage:
*       AR0      Used for comparisons
*       AR1      Used for pgm pulse count
*       AR2      Used for row banz loop
*       FL_ADRS  Used for flash address
*       FL_DATA  Used for flash data
*       BASE_0   Used for row-done flag
*       BASE_1   Used for row start address
*       BASE_2   Used for byte mask.
*****
GCLR:
        SETC      INTM      ;Disable all ints.
        CLRC      SXM       ;Disable sign extension.
        SPLK      #0,ERROR  ;Reset error flag
        LACL      SEG_ST    ;Get segment start address.
        SACL      FL_ADRS   ;Save as current address.
        AND       #04000h   ;Get array start address.

```

```

        SACL      FL_ST          ;Save array start address.
        LACL      FL_ADRS       ;Get segment start address.
NEWROW   ;*****Begin a new row.*
        SACL      BASE_1        ;Save row start address.
        LAR       AR1,#0        ;Init pulse count to zero.
SAMEROW  ;*****Same row, next pulse.*
        SPLK      #1,BASE_0     ;Set row done flag = 1(True).
        LACL      BASE_1        ;Get row start address.
        SACL      FL_ADRS       ;Save as current address.
        LAR       AR2,#31       ;Init row index.
*****Repeat the following code 32 times until end of row.*
LOBYTE   ;*****First, do low byte.*
        SPLK      #0FFh,BASE_2  ;Get lo-byte mask.
        CALL      PRG_BYTE      ;Check/Program lo-byte
        SPLK      #0FF00h,BASE_2 ;Get hi-byte mask.
        CALL      PRG_BYTE      ;Check/Program hi-byte.
NEXTWORD ;*****Next word in row.
        LACL      FL_ADRS       ;Load address for next word.
        ADD       #1            ;Increment address.
        SACL      FL_ADRS       ;Save as current address.
        MAR       *,AR2        ;Point to row index.
        BANZ     LOBYTE        ;Do next word,and dec AR2.
*****Reached end of row. Check if row done.*
        BIT      BASE_0,15     ;Get row_done flag.
        BCND     ROW_DONE,TC    ;If 1, then row is done.
        MAR     *,AR1          ;Else, row is not done, so
        MAR     *+             ;inc row pulse count.
        LAR     ARO,#MAX_PGM    ;Check if passed allowable max.
        CMPR    2              ;If AR1>MAX_PGM, then
        BCND    EXIT,TC        ;fail, don't continue.
        B       SAMEROW        ;else, go to beginning
                                ;of same row.
*****If row done, then check if Array done.*
ROW_DONE ;Check if end of array.
        SUB     SEG_END        ;Subtract segment end address.
        BCND    DONE,GEQ       ;If >0, then done.
*****Else, go to next row.*
        LACL    FL_ADRS        ;Get current address.
        B      NEWROW          ;Start new row.
*****If here, then done.
DONE    CALL    ARRAY          ;Access flash in array mode.
        RET
*****If here, then unit failed to program.*
EXIT    SPLK   #1,ERROR        ;Update error flag.
        B      DONE            ;Get outa here.
        .page
*****
*   THIS SECTION PROGRAMS THE VALUE STORED IN FL_DATA INTO   *
*   THE FLASH ADDRESS DEFINED BY FL_ADRS.                    *
*                                                             *
*   The following resources are used for temporary storage:   *
*       AR6   Parameter passed to Delay.                      *
*       SPAD1 Flash program and STOP commands.                *

```

```

*          SPAD2 Flash program + EXE command.          *
*****
EXE_PGM                                         ;*
    CALL   ARRAY                               ;ACCESS ARRAY      *
*LOAD WADRS AND WDATA                          **
    LACL   FL_ADRS                            ;ACC => PROGRAM ADRS  *
    TBLW   FL_DATA                            ;LOAD WADRS AND WDATA *
    CALL   REGS                               ;ACCESS FLASH REGS   *
*SET UP WRITE COMMAND WORDS                    **
    LACL   PROTECT                            ;GET SEGMENT PROTECT MASK **
    OR     #WR_CMND                          ;OR IN WRITE COMMAND  **
    SACL   SPAD1                              ;SPAD1 = WRITE COMMAND **
    OR     #WR_EXE                            ;OR IN EXEBIN COMMAND **
    SACL   SPAD2                              ;SPAD2 = WRITE EXE COMMAND **
*
    LACL   FL_ST                              ;ACC => 0 (FLASH0)    *
* ACTIVATE WRITE BIT                            **
    TBLW   SPAD1                              ;EXECUTE COMMAND      **
    LAR    AR6,#D10                           ;SET DELAY            **
    CALL   DELAY,*,AR6 ;WAIT                  **
* SET EXEBIN BIT                                **
    TBLW   SPAD2                              ;EXECUTE COMMAND      **
    LAR    AR6,#D100                           ;SET DELAY            **
    CALL   DELAY,*,AR6 ;WAIT                  **
* STOP WRITE OPERATION                          *
    SPLK   #0,SPAD1                           ;SHUTDOWN WRITE OPERATION *
    TBLW   SPAD1                              ;EXECUTE COMMAND      *
    LAR    AR6,#D10                           ;SET DELAY            *
    CALL   DELAY,*,AR6 ;WAIT                  *
*
    RET                                         ;RETURN TO CALLING SEQUENCE*
*****
    .page
*****
* ACTIVATE VER0 ON FLASH READS                  *
* LOADS FLASH WORD AT ADDR FL_ADRS TO FL_DATA. *
* Uses SPAD1 for temporary storage of flash commands. *
*****
SET_RD_VER0                                     ;*
    CALL   REGS                               ;ACCESS FLASH REGISTERS *
    LACL   FL_ST                              ;ACC => FLASH         *
    SPLK   #VER0,SPAD1                       ;ACTIVATE VER0        *
    TBLW   SPAD1                              ;EXECUTE COMMAND*     *
    LAR    AR6,#D10                           ;SET DELAY            *
    CALL   DELAY,*,AR6 ;WAIT                  *
    CALL   ARRAY                               ;ACCESS FLASH ARRAY   *
    LACL   FL_ADRS                            ;POINT TO ADRS        *
    TBLR   FL_DATA                            ;GET FLASH WORD 1x read *
    TBLR   FL_DATA                            ;2x read              *
    TBLR   FL_DATA                            ;3x read              *
    CALL   REGS                               ;ACCESS FLASH REGISTERS *
    LACL   FL_ST                              ;ACC => FLASH         *
    SPLK   #STOP,SPAD1                       ;DEACTIVATE VER0      *

```

```

        TBLW      SPAD1          ;EXECUTE COMMAND          *
        LAR       AR6,#D10      ;SET DELAY              *
        CALL     DELAY,* ,AR6   ;WAIT                  *
        CALL     ARRAY         ;ACCESS FLASH ARRAY        *
        RET      ;RETURN TO CALLING SEQUENCE*
*****
*****
*   PRG_BYTE: Programs hi or lo byte depending on *
*           byte mask (BASE_2).                  *
*****
PRG_BYTE:
        CALL     SET_RD_VER0   ;Read word at VER0 level.
        LACL    BASE_2        ;Get lo/hi byte mask.
        AND     FL_DATA       ;Xor with read-back value.
        BCND   PB_DONE,EQ     ;If zero, then done.
        XOR    #0FFFFh        ;else, mask off good bits.
        SACL   FL_DATA        ;New data.
        CALL   EXE_PGM        ;PGM Pulse.
        SPLK  #0,BASE_0       ;Set row done flag = 0(False).
PB_DONE RET
*****
        .end

```

A.1.3 Erase Algorithm, SERA20.ASM

This code is an implementation of the erase algorithm described in section 3.3 on page 3-10.

Memory section: **fl_ers**

Entry point: **GERS**

Parameters to be declared and initialized by the calling code are:

- PROTECT defines the values of bits 8–15 of SEG_CTR during the erase algorithm.
- SEG_ST defines the start address of the flash array to be erased.
- SEG_END defines the end address of the flash array to be erased.

Return value: **ERROR** (@BASE+15); 0 = Pass, 1 = Fail

```

*****
*   ERASE subroutine                                     **
*                                                                 **
*   TMS320F2XX Flash Utilities.                         **
*       Revision: 2.0, 9/10/97                          **
*       Revision: 2.1, 1/31/98                          **
*                                                                 **
*   Filename: sera20.asm                                **
*                                                                 **
*   Called by: c2xx_bex.asm or flash application programs. **
*                                                                 **
*   !!CAUTION - INITIALIZE DP BEFORE CALLING THIS ROUTINE!! **
*                                                                 **
*   Function: Erases one or more contiguous segments of  **
*             flash array 0/1 as specified by the       **
*             following variables.                      **
*             SEG_ST   Segment start address           **
*             SEG_END  Segment end address            **
*             PROTECT  Sector protect enable          **
*                                                                 **
*   The algorithm used is XOR-VER1, which means that in **
*   addition to the VER1 read mode, an XOR readback is used **
*   to gain more margin. During the read portion of the **
*   erase, two reads are performed for each address; for the **
*   first read, all address bits are complemented using a **
*   logical XOR with the array end address. The data read **
*   during the first read is discarded, and the second read **
*   is performed on the actual address. This scheme     **
*   simulates the worst-case branching condition for code **
*   executing from the flash array.                    **

```

```

* The erase pulse duration is 7ms, and a maximum of      **
* 1000 pulses is applied to the array.                    **
*                                                         **
* The following resources are used for temporary storage:  **
*   AR0          Used for comparisons                      **
*   AR1          Used for erase pulse count                **
*   AR2          Used for main banz loop                  **
*   AR6          Parameter passed to DELAY                **
*   BASE_0       Parameter passed to Set_mode             **
*   BASE_1       Used for flash address.                  **
*   BASE_2       Used for flash data                      **
*   BASE_3       Used for flash checksum                  **
*   BASE_4       Used for segment size                    **
*   BASE_5       Flash Erase command                      **
*   BASE_6       Flash Erase+EXE command                  **
*****
                .include "svar20.h" ;defines variables for flash0
                                ;or for flash1 array
*
MAX_ER   .set   1000           ;Allow only 1000 erase pulses.
VER1     .set   8              ;VER1 command.
ER_CMND  .set   2              ;ERASE COMMAND WORD
ER_EXE   .set   043h          ;ERASE EXEBIN COMMAND WORD
INV_ER   .set   018h          ;INVERSE ERASE COMMAND WORD
FL_WR    .set   6              ;FLASH WRITE COMMAND WORD
FLWR_EX  .set   047h          ;FLASH WRITE EXEBIN COMMAND WORD
STOP     .set   0              ;RESET REGISTER COMMAND WORD
                .def   GERS
                .ref   PROTECT,SEG_ST,SEG_END
                .ref   DELAY,REGS,ARRAY
                .sect  "fl_ers"
*****
* GERS: This routine performs an erase to                  *
* xorver1 level. The Seg to erase is defined by           *
* the vars SEG_ST and SEG_END. The following              *
* resources are used for temporary storage:                *
*   AR0          Used for comparisons                      *
*   AR1          Used for erase pulse count                *
*   AR2          Used for main banz loop                  *
*   BASE_0       Parameter passed to Set_mode             *
*   BASE_1       Used for flash address.                  *
*   BASE_2       Used for flash data                      *
*   BASE_3       Used for flash checksum                  *
*   BASE_4       Used for segment size                    *
*****
GERS:
*****
* Code initialization section                               *
* Initialize test loop counters:                           *
*   AR1 is the number of ERASE pulses.                     *
*****
                SETC   INTM           ;Disable all maskable ints.
                SETC   SXM           ;Enable sign extension.

```

```

        CLRC    OVM                ;Disable overflow mode.
        LACL   SEG_ST             ;Get segment start address.
        AND    #04000h           ;Get array start address.
        SACL   FL_ST             ;Save array start address.
        OR     #03FFFh           ;Get array end address.
        SACL   FL_END            ;Save array end address.
        SPLK   #0,ERROR          ;Reset error flag
        LAR    AR1,#0            ;Set erase count to 0.
        SPLK   #STOP, BASE_0     ;Stop command.
        CALL   SET_MODE          ;Disable any flash cmds.
XOR_ERASE
** Compute checksum for flash, using address complementing.**
        LACC   SEG_END
        SUB    SEG_ST
        SAC    BASE_4            ;Segment length-1.
        LAR    AR2,BASE_4        ;load n-1 to loop n times.
        ADD    #1
        SACL   BASE_4            ;Segment length.
        SPLK   #VER1,BASE_0      ;VER1 command.
        CALL   SET_MODE          ;Set VER1 mode.
        MAR    *,AR2
        BLDD   #SEG_ST,BASE_1     ;Segment start address.
        SPLK   #0,BASE_3         ;Clear checksum.
RD1_LOOP
        LACC   BASE_1            ;ACC => CURRENT ADDR.
        XOR    FL_END            ;XOR addr with flash end addr.
        TBLR   BASE_2            ;Dummy Read.
        LACC   BASE_1            ;Get actual addr again.
        TBLR   BASE_2            ;True Read.
        ADD    #1                ;Increment flash addr.
        SACL   BASE_1            ;Store for next read.
        LACC   BASE_3            ;Get old check sum.
        ADD    BASE_2            ;ACC=>ACC+FL_DATA.
        SACL   BASE_3            ;Save new check sum.
        BANZ   RD1_LOOP,*-
        ADD    BASE_4            ;Should make ACC = 0 for
                                ;erased array.
        BCND   XOR_ERFIN,EQ      ;If BASE_3 = 0, finished.

***** If not erased, apply an erase pulse.
        CALL   ERASE_A           ;Else, pulse it again.
        MAR    *,AR1            ;ARP->AR1 (Erase pulse count)
        MAR    *+                ;Increment Erase count.
        LAR    AR0,#MAX_ER
        CMPR2                                ;If AR1>MAX_ER then
        BCND   EXIT,TC           ;fail, don't continue erasing.
        B      XOR_ERASE         ;Else, check again.
***** If here, then erase passed; now check for depletion.
XOR_ERFIN
        SPLK   #STOP, BASE_0     ;Stop command.
        CALL   SET_MODE          ;Disable any flash cmds.
        CALL   INV_ERASE        ;Check for depletion.
DONE    RET                      ;Return to calling code.

```



```

**** If here, then an error has occurred.
EXIT  SPLK  #1,ERROR           ;Update error flag
      SPLK  #STOP,BASE_0       ;Stop command.
      CALL  SET_MODE           ;Disable any flash cmds.
      B     DONE               ;Get outa here.
*****
      .page
*****
*   SET_MODE: This routine sets the flash in the  *
*   mode specified by the contents of BASE_0. This *
*   can be used for VER0,VER1,INVERASE, or STOP.  *
*           AR6: Parameter passed to DELAY.      *
*****
SET_MODE
      CALL  REGS               ;ACCESS FLASH REGS
      LACL  FL_ST              ;ACC => SEG_CTR.
      TBLW  BASE_0            ;Activate MODE.
      LAR   AR6,#D10          ;SET DELAY
      CALL  DELAY,*,AR6       ;WAIT
      CALL  ARRAY             ;ACCESS FLASH ARRAY
      RET
*****
*   INV_ERASE: This routine is used to check for  *
*   depletion in the flash array.                *
*           AR2      Used for main banz loop      *
*           BASE_0   Parameter passed to Set_mode *
*           BASE_1   Used for flash address       *
*           BASE_2   Used for flash data         *
*****
INV_ERASE
      SPLK  #INV_ER,BASE_0
      CALL  SET_MODE           ;Set inverse-erase mode.
      BLDD  #FL_ST,BASE_1     ;Array start address.
      LAR   AR2,#31           ;Loop count.
      MAR   *,AR2
NEXT_IVERS
      LACL  BASE_1            ;Get address.
      TBLR  BASE_2            ;Dummy read.
      TBLR  BASE_2            ;Read data.
      ADD   #1                ;Increment address.
      SACL  BASE_1            ;Save address.
      ZAC
      ADD   BASE_2            ;Add data.
      BCND  EXIT,NEQ          ;If ACC<>0, then fail.
*Else continue, until until done with row.
      BANZ  NEXT_IVERS        ;Loop 32 times.
      SPLK  #STOP,BASE_0       ;Stop command.
      CALL  SET_MODE           ;Disable any flash cmds.
      RET   ;If here then test passed.
      .page
*****
*   ERASE_A: This subroutine applies one erase pulse to the  *
*   flash array.                                           *

```

```

*
* The following resources are used for temporary storage:
*   BASE_0   Flash STOP command, and FFFF for WDATA.
*   BASE_5   Flash erase command.
*   BASE_6   Flash erase + EXE command.
*****
ERASE_A
*   SET UP FLASH ERASE COMMANDS FOR PROTECT MASK.
*       LACL   PROTECT           ;GET SEGMENT PROTECT MASK
*       OR     #ER_CMND         ;OR IN ERASE COMMAND
*       SACL   BASE_5           ;BASE_5 = ERASE COMMAND
*       OR     #ER_EXE          ;OR IN EXEBIN COMMAND
*       SACL   BASE_6           ;BASE_6 = ERASE EXE COMMAND
*
*   MUST LOAD WDATA WITH FFFF.
*       SPLK   #0FFFFh,BASE_0   ;WDATA VALUE FOR ERASE
*       LACC   FL_ST             ;ACC => FLASH
*       TBLW   BASE_0           ;SET WDATA = FFFF
*
*   THIS SECTION ACTIVATES THE WRITE COMMAND.
*       SPLK   #STOP,BASE_0     ;Stop command.
*       CALL   SET_MODE         ;Disable any flash cmds.
*       CALL   REGS             ;ACCESS FLASH REGS
*       LACC   FL_ST             ;ACC => FLASH
*       TBLW   BASE_5           ;ACTIVATE ERASE
*       LAR    AR6,#D10         ;SET DELAY
*       CALL   DELAY,*,AR6      ;WAIT
*
*   THIS SECTION ACTIVATES THE EXEBIN COMMAND.
*       TBLW   BASE_6           ;START ERASURE
*       LAR    AR6,#D7K         ;SET DELAY to 7 ms
*       CALL   DELAY,*,AR6      ;WAIT
*       SPLK   #STOP,BASE_0     ;STOP COMMAND
*       CALL   SET_MODE         ;STOP ERASE
*       RET                                ;RETURN TO CALLING CODE
*****
.end

```

A.1.4 Flash-Write Algorithm, SFLW20.ASM

This code is an implementation of the flash-write algorithm described in section 3.4 on page 3-14.

Memory section: **fl_wrt**

Entry point: **FLWS**

Parameters to be declared and initialized by the calling code are:

- PROTECT defines the values of bits 8–15 of SEG_CTR during the flash-write algorithm.
- SEG_ST defines the start address of the flash array to be recovered.
- SEG_END defines the end address of the flash array to be recovered.

Return value: **ERROR (@BASE+15)** 0=Pass, 1=Fail

```

*****
** FLASH-WRITE subroutine                                     **
*                                                           **
* TMS320F2XX Flash Utilities.                               **
* Revision: 2.0, 9/10/97                                    **
* Revision: 2.1, 1/31/98                                    **
*                                                           **
* Filename: sflw20.asm                                      **
*                                                           **
* Called by : c2xx_bfx.asm or flash application programs.  **
*                                                           **
* !!CAUTION - INITIALIZE DP BEFORE CALLING THIS ROUTINE!!  **
*                                                           **
* Function: Performs flash writes on flash array 0/1 as    **
*           specified by the following vars:                **
*           SEG_ST   Array segment start address           **
*           PROTECT  Sector protect enable                 **
*                                                           **
* The flash-write pulse duration used is 14 ms, and a     **
* maximum of 10000 pulses is applied until the device     **
* passes the depletion test.                               **
*                                                           **
* The following resources are used for temp storage:       **
*   AR0      Used for comparison                           **
*   AR1      Flash-Write Pulse Count                       **
*   AR2      Used for main BANZ loop                       **
*   AR6      Parameter passed to DELAY                    **
*   BASE_0   Parameter passed to SET_MODE                 **
*   BASE_1   Used for flash address                       **
*   BASE_2   Used for flash data                          **

```

```

*      BASE_3      Used for EXE + flw cmd      *
*****
      .include "svar20.h"      ;defines variables for flash0
                               ;or for flash1 array

*
MAX_FLW      .set      10000      ;Allow only 10000 flw pulses.
INV_ER      .set      018h      ;INVERSE ERASE COMMAND WORD
FLWR      .set      6      ;FLASH WRITE COMMAND WORD
FLWR_EX      .set      047h      ;FLASH WRITE EXEBIN COMMAND WORD
STOP      .set      0      ;RESET REGISTER COMMAND WORD

      .def      FLWS
      .ref      PROTECT,SEG_ST,SEG_END
      .ref      DELAY,REGS,ARRAY
      .sect "fl_wrt"
*****
*      FLWS: This routine is used to check for bits      *
*      in depletion mode. If any are found, flash-      *
*      write is used to recover.      *
*      AR1      Flash-write pulse count.      *
*      AR2      Used for main banz loop.      *
*      BASE_0 Parameter passed to Set_mode.      *
*      BASE_1 Used for flash address.      *
*      BASE_2 Used for flash data.      *
*****
FLWS:
*****
*      Code initialization section      *
*      Initialize test loop counters:      *
*      AR1 is the number of flash-write pulses.      *
*****
      SETC      INTM      ;Disable maskable ints.
      LACL      SEG_ST      ;Get segment start address.
      AND      #04000h      ;Get array start address.
      SACL      FL_ST      ;Save array start address.
      SPLK      #0,ERROR      ;Reset error flag.
      LAR      AR1,#0      ;Set FLW count to 0.
      SPLK      #STOP,BASE_0      ;Flash STOP command.
      CALL      SET_MODE      ;Disable any flash commands.
INV_ERASE
      SPLK      #INV_ER,BASE_0
      CALL      SET_MODE      ;Set inverse-erase mode.
      BLDD      #FL_ST,BASE_1      ;Array start address.
      LAR      AR2,#31      ;Loop count.
      MAR      *,AR2
NEXT_IVERS
      LACL      BASE_1      ;Get address.
      TBLR      BASE_2      ;Dummy read.
      TBLR      BASE_2      ;Dummy read.
      TBLR      BASE_2      ;Read data.
      ADD      #1      ;Increment address.
      SACL      BASE_1      ;Save address.
      ZAC
      ADD      BASE_2      ;Add data.

```

```

        BCND    FL_WRITE, NEQ ;If ACC<>0, then flwrite.
*Else, continue until until done with row.
        BANZ   NEXT_IVERS    ;Loop 32 times.
        SPLK   #STOP,BASE_0  ;Flash STOP command.
        CALL  SET_MODE      ;Disable flash commands.
                                ;If here then test passed.
DONE    RET                ;Return to calling code.
* If here, then an error has occurred.
EXIT   SPLK   #1,ERROR      ;Update error flag
        SPLK   #STOP,BASE_0  ;Flash STOP command.
        CALL  SET_MODE      ;Disable flash commands.
        CALL  ARRAY         ;ACCESS FLASH ARRAY
        B     DONE          ;Get outa here.
        .page
*****
*   FL_WRITE: This routine performs a fl_write on *
*   the flash until a maximum is reached. The *
*   array is defined by the variable FL_ST *
*   and the segment(s) is defined by the PROTECT *
*   mask. The following resources are used for *
*   temporary storage: *
*       AR0    Used for comparison *
*       AR1    Used for pulse count (Global) *
*       AR6    Parameter passed to DELAY *
*       BASE_0 Parameter passed to SET_MODE *
*       BASE_2 Used for flw cmd *
*       BASE_3 Used for EXE + flw cmd *
*****
FL_WRITE
        SPLK   #STOP,BASE_0  ;Flash STOP command.
        CALL  SET_MODE      ;Disable flash commands.
        LACL  PROTECT      ;Get sector_prot mask.
        OR    #FLWR        ;Or in fl_write cmd.
        SACL  BASE_2       ;BASE_2 = fl_write cmd.
        OR    #FLWR_EX     ;Or in EXE + fl_write cmd.
        SACL  BASE_3       ;BASE_3 = EXE + fl_write cmd.
*Set the flash-write command.
        CALL  REGS         ;Access flash regs.
        LACC  FL_ST        ;ACC => SEG_CTL.
        TBLW  BASE_2       ;Initiate fl_write.
        LAR   AR6,#D10     ;Set delay.
        CALL  DELAY,*,AR6  ;Wait,10US flw stabilization time.
*Set the EXE bit (start flash-write pulse).
        TBLW  BASE_3       ;Start flw pulse.
        LAR   AR6,#D7K     ;Set delay to 7 ms.
        CALL  DELAY,*,AR6  ;WAIT,7 ms.
        LAR   AR6,#D7K     ;Set delay to 7 ms.
        CALL  DELAY,*,AR6  ;WAIT 7 ms.
*A 14-mS flash write pulse has been applied.
        SPLK   #STOP,BASE_0  ;Flash STOP command.
        CALL  SET_MODE      ;Disable flash commands.
        MAR   *,AR1
        MAR   *+           ;Increment flw count.

```

```
        LAR    AR0,#MAX_FLW
        CMPR   2          ;If AR1>MAX_FLW then
        BCND  EXIT,TC    ;Fail, don't continue recovery.
        B     INV_ERASE  ;Else, perform iverase again.
*****
*  SET_MODE: This routine sets the flash in the *
*  mode specified by the contents of BASE_0. This *
*  can be used for VER0,VER1,INVERASE,or STOP.  *
*****
SET_MODE
        CALL  REGS        ;ACCESS FLASH REGS
        LACL  FL_ST      ;ACC => SEG_CTR.
        TBLW  BASE_0    ;Activate MODE.
        LAR   AR6,#D10   ;SET DELAY
        CALL  DELAY,*,AR6 ;WAIT
        CALL  ARRAY      ;ACCESS FLASH ARRAY
        RET
*****
        .end
```

A.1.5 Programming Algorithm, SPGM20.ASM

This code is an implementation of the program algorithm described in section 3.2 on page 3-4.

Memory section: **fl_prg**

Entry point: **GPGMJ**

Parameters to be declared and initialized by the calling code are:

- PRG_bufaddr defines the destination start address.
- PRG_length defines the source buffer length.
- PRG_paddr defines the source buffer start address (data space).
- PROTECT defines the values of bits 8–15 of SEG_CTR during the programming algorithm.

Return value: **ERROR** (@BASE+15); 0 = Pass, 1 = Fail

```

*****
** PROGRAM Subroutine                               **
*                                                    **
* TMS320F2XX Flash Utilities.                       **
*   Revision: 2.0, 9/10/97                          **
*   Revision: 2.0b, 12/5/97                         **
*   Revision: 2.1, 1/31/98                         **
*                                                    **
* Filename: spgm20.asm                             **
*                                                    **
* Called by: c2xx_bpx.asm or flash application programs. **
*                                                    **
* !!CAUTION - INITIALIZE DP BEFORE CALLING THIS ROUTINE!! **
*                                                    **
* Function: This routine programs all or part of the **
*           flash as specified by the variables:    **
*           PRG_paddr   Destination start address  *
*           PRG_length  Source buffer length       *
*           PRG_bufaddr Source buffer start address *
*                                                    *
* The algorithm used is "row-horizontal", which means that *
* an entire flash row (32 words) is programmed in parallel.*
* This method provides better uniformity of programming *
* levels between adjacent bits than if each address were *
* programmed independently. The algorithm also uses a *
* 3-read check for VERO margin (i.e., the flash location is*
* read three times and the first two values are discarded.)*
* This provides low-freq read-back margin on programmed *

```

```

* bits. For example, if the flash is programmed using a      *
* CLKOUT period of 50 ns, the flash can be reliably read    *
* back over the CLKOUT period range of 50 ns to 150 ns     *
* (6.67MHz-20 MHz). The programming pulse duration is      *
* 100 us, and a maximum of 150 pulses is applied per row.  *
*
* The following variables are used for temp storage:        *
*   AR0           Used for comparisons                      *
*   AR1           Used for pgm pulse count                  *
*   AR2           Used for row banz loop                    *
*   AR3           Used for buffer addr index                *
*   AR4           Used for flash address.                   *
*   AR6           Parameter passed to Delay                 *
*   SPAD1         Flash program and STOP commands          *
*   SPAD2         Flash program + EXE command              *
*   FL_ADRS       Used for flash address                   *
*   FL_DATA       Used for flash data                       *
*   BASE_0        Used for row-done flag                    *
*   BASE_1        Used for row start address                 *
*   BASE_2        Used for row length-1                     *
*   BASE_3        Used for buffer/row start addr            *
*   BASE_4        Used for destination end addr             *
*   BASE_5        Used for byte mask                        *
*****
        .include "svar20.h"
*
MAX_PGM .set 150 ;Allow only 150 pulses per row.
VER0    .set 010h ;VER0 command.
WR_CMND .set 4 ;Write command.
WR_EXE  .set 045h ;Write EXEBIN command.
STOP    .set 0 ;Reset command.
        .def GPGMJ
        .ref PRG_bufaddr,PRG_length,PRG_paddr
        .ref PROTECT,DELAY,REGS,ARRAY
        .sect "fl_prg"
*****
* GPGMJ: This routine programs all or part of                *
* the flash as specified by the variables:                   *
* PRG_paddr Destination start address                        *
* PRG_length Source buffer length                           *
* PRG_bufaddr Buffer start address                           *
*
* The following variables are used for temp                  *
* storage:                                                  *
*   AR0           Used for comparisons                      *
*   AR1           Used for pgm pulse count                  *
*   AR2           Used for row banz loop                    *
*   AR3           Used for buffer addr index                *
*   FL_ADRS       Used for flash address                   *
*   FL_DATA       Used for flash data                       *
*   BASE_0        Used for row-done flag                    *
*   BASE_1        Used for row start address                 *
*   BASE_2        Used for row length-1                     *

```



```

*      BASE_3      Used for buffer/row start addr      *
*      BASE_4      Used for destination end addr      *
*      BASE_5      Used for byte mask                *
*****
GPGMJ: SPLK   #0,IMR           ;MASK ALL INTERRUPTS
      SETC   INTM             ;GLOBALLY MASK ALL INTERRUPTS
      SPLK   #0,ERROR         ;Initialize error flag (no error).
      LACL   PRG_paddr        ;Get destination start address.
      SACL   FL_ADRS          ;Save as current address.
      ADD    PRG_length       ;Determine destination end addr.
      SUB    #1               ;
      SACL   BASE_4           ;Save destination end addr.
      LACL   PRG_paddr        ;Get destination start addr.
      LAR    AR3,PRG_bufaddr  ;Get buffer start address.
*****Begin a new row.*
NEWROW
      SACL   BASE_1           ;Save row start address.
      SAR    AR3,BASE_3       ;Save buffer/row start address.
      LAR    AR1,#0           ;Init pulse count to zero.
      SPLK   #31,BASE_2       ;Init row length-1 to 31.
      AND    #001Fh          ;Is start addr on row boundary?
      CC     ADJ_ROW,NEQ      ;If not then adjust row length.
      LACL   BASE_1           ;Get row start address.
      OR     #001Fh          ;Get row end address.
      SUB    BASE_4           ;Is end address on row boundary?
      CC     ADJ_ROW,GT       ;If not then adjust row length.
*****Same row, next pulse.*
SAMEROW  SPLK   #1,BASE_0     ;Set row done flag = 1(True).
          LACL   BASE_1       ;Get row start address.
          SACL   FL_ADRS      ;Save as current address.
          LAR    AR3,BASE_3   ;Get buffer/row start addr.
          LAR    AR2,BASE_2   ;Init row index.
** Repeat the following code 32 times or until end of row.*
LOBYTE   ;*****First, do low byte.*
          CALL   SET_MODULE,AR4 ;Determine which flash module.
          SPLK   #0FFh,BASE_5 ;Set lo-byte mask.
          CALL   PRG_BYTE      ;Check/Program lo-byte.
          SPLK   #0FF00h,BASE_5 ;Set hi-byte mask.
          CALL   PRG_BYTE      ;Check/Program hi-byte.
NEXTWORD ;*****Next word in row.
          LACL   FL_ADRS      ;Load address for next word.
          ADD    #1           ;Increment address.
          SACL   FL_ADRS      ;Save as current address.
          MAR    *,AR3        ;ARP -> buffer addr index.
          MAR    *+,AR2       ;Inc, and ARP -> row index.
          BANZ  LOBYTE        ;Do next word,and dec AR2.
** Reached end of row. Check if row done. *
          BIT   BASE_0,15     ;Get row_done flag.
          BCND  ROW_DONE,TC   ;If 1 then row is done.
          MAR    *,AR1        ;Else, row is not done, so
          MAR    *+           ;inc row pulse count.
          LAR    ARO,#MAX_PGM ;Check if passed allowable max.
          CMPR  2             ;If AR1>MAX_PGM then

```

```

        BCND  EXIT,TC          ;fail, don't continue.
        B     SAMEROW         ;else, go to beginning
                                ;of same row.
** If row done, then check if Array done. *
ROW_DONE
        LACL  FL_ADRS         ;Check if end of array.
        SUB   BASE_4         ;Subtract end addr.
        BCND  DONE, GT       ;If >0 then done.
** Else, go to next row. *
        LACL  FL_ADRS
        B     NEWROW         ;Start new row.
** If here, then done.
DONE
        CALL  ARRAY          ;Access flash in array mode.
        RET   ;Return to calling program.
** If here, then unit failed to program. *
EXIT   SPLK  #1,ERROR        ;Update error flag (error).
        B     DONE          ;Get outa here.
*****
        .page
*****
* ADJ_ROW: This routine is used to adjust the *
* row length, if the start or end address of *
* code being programmed does not fall on a row *
* boundary. The row length is passed in the *
* BASE_2 variable, and the adjustment value to *
* be subtracted is passed in the accumulator. *
*****
ADJ_ROW
        NEG   ;Take twos complement.
        ADD   BASE_2         ;Add row length.
        SACL  BASE_2         ;Save new row length.
        RET
*****
* SET_MODULE: This routine is used to point to *
* the appropriate flash array control register *
* This is only important for 'F2XX devices with *
* multiple flash modules like the 320F206. The *
* variable FL_ST is returned with the correct *
* register address. *
* The following resources are used *
* temporarily: *
*   AR0   Used for comparisons *
*   AR4   Used for flash address *
*****
SET_MODULE
        LAR   AR4,FL_ADRS    ;AR4 = current address.
        SPLK  #0,FL_ST       ;FL_ST = FLASH0 CTRL REGS
        LAR   AR0,#4000H     ;AR0 = compare value.
        CMPR  1              ;If AR4 < AR0 then
                                ;FL_ADRS < 4000H; SET TC
        BCND  FL0,TC         ;Address is in FL0.
*                               ;Else address is in FL1.

```

```

        SPLK    #04000h,FL_ST;FL_ST = FLASH1 CTRL REGS
FL0     RET
*****
        .page
*****
*   THIS SECTION PROGRAMS THE VALUE STORED IN FL_DATA INTO   *
*   THE FLASH ADDRESS DEFINED BY FL_ADRS.                     *
*
*   The following resources are used for temporary storage:   *
*   AR6      Parameter passed to Delay                        *
*   SPAD1    Flash program and STOP commands                 *
*   SPAD2    Flash program + EXE command.                   *
*****
EXE_PGM                                ;
*
        CALL   ARRAY                                ;ACCESS ARRAY
*
*   LOAD WADRS AND WDATA
        LACL   FL_ADRS                                ;ACC => PROGRAM ADRS
        TBLW  FL_DATA                                ;LOAD WADRS AND WDATA
        CALL  REGS                                  ;ACCESS FLASH REGS
*
*   SET UP WRITE COMMAND WORDS
        LACL  PROTECT                                ;GET SEGMENT PROTECT MASK
        OR   #WR_CMND                                ;OR IN WRITE COMMAND
        SACL  SPAD1                                  ;SPAD1 = WRITE COMMAND
        OR   #WR_EXE                                 ;OR IN EXEBIN COMMAND
        SACL  SPAD2                                  ;SPAD2 = WRITE EXE COMMAND
        LACL  FL_ST                                  ;ACC => (FLASH)
*
*   ACTIVATE WRITE BIT
        TBLW  SPAD1                                ;EXECUTE COMMAND
        LAR   AR6,#D10                              ;SET DELAY
        CALL  DELAY,*,AR6 ;WAIT
*
*   SET EXEBIN BIT
        TBLW  SPAD2                                ;EXECUTE COMMAND
        LAR   AR6,#D100                             ;SET DELAY
        CALL  DELAY,*,AR6 ;WAIT
*
*   STOP WRITE OPERATION
        SPLK  #0,SPAD1                                ;SHUT DOWN WRITE OPERATION
        TBLW  SPAD1                                ;EXECUTE COMMAND
        TBLW  SPAD1                                ;EXECUTE COMMAND
        LAR   AR6,#D10                              ;SET DELAY
        CALL  DELAY,*,AR6 ;WAIT
*
        RET    ;RETURN TO CALLING SEQUENCE
*****
        .page
*****
*   ACTIVATE VER0 ON FLASH READS
*   LOADS FLASH WORD AT ADDR FL_ADRS TO FL_DATA.
*   Uses SPAD1 for temporary storage of flash commands.
*****
SET_RD_VER0                                ;
        CALL  REGS                                ;ACCESS FLASH REGISTERS

```

```

        LACL  FL_ST          ;ACC => FLASH          *
        SPLK  #VER0,SPAD1   ;ACTIVATE VER0        *
        TBLW  SPAD1         ;EXECUTE COMMAND       *
        LAR   AR6,#D10      ;SET DELAY            *
        CALL  DELAY,*,AR6   ;WAIT                  *
        CALL  ARRAY        ;ACCESS FLASH ARRAY     *
        LACL  FL_ADRS       ;POINT TO ADRS        *
        TBLR  FL_DATA       ;GET FLASH WORD 1x read *
        TBLR  FL_DATA       ; 2x read             *
        TBLR  FL_DATA       ; 3x read             *
        CALL  REGS         ;ACCESS FLASH REGISTERS *
        LACL  FL_ST          ;ACC => FLASH          *
        SPLK  #STOP,SPAD1   ;DEACTIVATE VERO      *
        TBLW  SPAD1         ;EXECUTE COMMAND       *
        LAR   AR6,#D10      ;SET DELAY            *
        CALL  DELAY,*,AR6   ;WAIT                  *
        CALL  ARRAY        ;ACCESS FLASH ARRAY     *
        RET    ;RETURN TO CALLING SEQUENCE        *
*****
        .page
*****
*   PRG_BYTE: Programs hi or lo byte depending on*
*           byte mask (BASE_5).                  *
*****
PRG_BYTE:
        CALL  SET_RD_VER0   ;Read word at VER0 level.
        MAR  *,AR3         ;ARP -> buffer addr index.
        LACL  *             ;Get word to program.
        XOR  FL_DATA       ;Xor with read-back value.
        AND  BASE_5        ;Mask off hi/lo byte.
        BCND PB_END,EQ     ;If zero then done.
        XOR  #0FFFFh       ;else, mask off good bits.
        SACL  FL_DATA       ;New data.
        CALL  EXE_PGM       ;PGM Pulse.
        SPLK  #0,BASE_0    ;Set row done flag = 0(False).
PB_END RET
*****
        .end

```

A.1.6 Subroutines Used By All Four Algorithms, SUTILS20.ASM

This assembly file includes two subroutines that change the flash module access mode and one subroutine that performs software delays. More details on the individual functions are given in the comments.

```

*****
** Delay And Access Mode Subroutines          **
*                                             **
* TMS320F2XX Flash Utilities.                **
*   Revision: 2.0, 9/10/97                    **
*   Revision: 2.1, 1/31/98                    **
*                                             **
* Filename: sutils20.asm                      **
*                                             **
* Called by:  These utilities are used by CLEAR,ERASE, **
*             PROGRAM algorithms written for F2xx  **
*             devices.                          **
* Function:  DELAY Delay loop specified by AR6.  **
*           REGS Clears MODE bit of F_ACCESS0/1 to **
*             access flash module control registers. **
*           ARRAY Sets MODE bit of F_ACCESS0/1 to access **
*             the flash array.                  **
*****
        .include "svar20.h"
        .def    DELAY,REGS,ARRAY
        .sect  "DLY"
*****
*Delays as follows:                          *
* LAR    AR6,#N          2 Cycles             *
* CALL  DELAY            4 Cycles             *
* RPT   #DLOOP 2*(N+1)  Cycles                *
* NOP   DLOOP*(N+1)     Cycles                *
* BANZ  DLY_LP  4*N+2   Cycles                *
* RET   4 Cycles                                             *
* ----- *
* = DLOOP(N+1)+6*N+14 Cycles *
* Set N and DLOOP appropriately to *
* get desired delay. *
*****
DELAY                ;AR6 = OUTER LOOP COUNT
DLY_LP    RPT    #DLOOP    ;APPROX 5US DELAY
        NOP
        BANZ  DLY_LP,*- ;LOOP UNTIL DONE
        RET                ;RETURN TO CALLING SEQUENCE
        .page
*****
* REGS    Clears MODE bit of F_ACCESS0/1 to **
*         access flash module control registers. **
*****
        .sect  "REG"
REGS

```

```

        SPLK    #0000h,SPAD2
*****The next instruction is for F240 only*****
        .if    F24X = 1            ;Assemble for F24X only.
        OUT    SPAD2,F24X_ACCS    ;Enable F240 flash reg mode.
                                      ;SPAD1 is dummy value.
        .endif
*****
        .if    F24X = 0            ;Assemble for F206 only.
        LACC   FL_ST
        SUB    #4000h
        BCND   reg1,geq           ;if address>= 4000h,set
                                      ;set reg mode for flash1 array
        OUT    SPAD2,F_ACCESS0    ;Change mode of flash0.
        RET
reg1    OUT    SPAD2,F_ACCESS1    ;Change mode of flash1.
        .endif
        RET                                ;RETURN TO CALLING SEQUENCE

        .page
*****
*   ARRAY Sets MODE bit of F_ACCESS0/1 to access **
*   the flash array.                               **
*****
        .sect  "ARY"
ARRAY
        SPLK   #0001h,SPAD2
*****The next instruction is for F240 only*****
        .if    F24X = 1            ;Assemble for F240 only.
        IN     SPAD1,F24X_ACCS    ;Enable F240 flash array mode.
                                      ;SPAD1 is dummy value.
        .endif
*****
        .if    F24X = 0            ;Assemble for F206 only.
        LACC   FL_ST
        SUB    #4000h
        BCND   ary1,geq          ;if address>= 4000h,set
                                      ;set reg mode for flash1 array
        OUT    SPAD2,F_ACCESS0    ;Change mode of flash0.
        RET
ary1    OUT    SPAD2,F_ACCESS1    ;Change mode of flash1.
        .endif
        RET                                ;RETURN TO CALLING SEQUENCE
        .end

```

A.2 C-Callable Interface to Flash Algorithms

The two functions `erase()` and `program()` are intended for in-application programming of the 'F20x/F24x flash module. These functions were written to be C callable, but they can also be called from assembly as long as the C stack calling convention is used.

```

*****
* This file contains two C-callable functions:
*   program(), and erase()
* These functions are used for programming and
* erasing the on-chip flash EEPROM of the 'F2XX
* product family.
*****
* The functions provide a C-callable, interface to
* the standard 'F2XX flash algorithms. They can
* also be used from assembly code, as long as the
* C stack calling convention is used. Since the
* standard flash algorithms are actually used to
* perform the various flash operations, they must
* must be combined with this code at link time.
*
* The erase function includes all the operations
* (clear+erase+flw) required to prepare the flash
* for programming. In addition to providing the
* C-callable interface, this function is very
* useful since it provides a single call to erase
* the flash memory.
* Since programming the device requires a single
* algorithm, the only purpose for the program()
* function is to provide a C-callable interface.
* The program() function transfers a specified
* block of data memory into a specified, erased
* flash array.
*
* The parameters for each function are described
* in detail below. Note these functions cannot
* reside in the same flash module that they are
* meant to modify.
*
*   10/29/97  Ruben D. Perez
*             DSP Applications Team
*             Texas Instruments, Inc.
*   03/20/98  Updated for inclusion in flash
*             technical reference.
*****

.title "C-callable Interface to 'F2XX Flash Algorithms*"
**C-callable functions defined in this file.
.global  _erase,  _program

```

```

**Variables included from flash algorithms.
    .include "svar20.h" ;Variable declarations
    .ref GCLR ;References clear algo.
    .ref GPGMJ ;References program algo.
    .ref GERS ;References erase algo.
    .ref FLWS ;References flash-write algo.
**Parameters used by flash algorithms.
    .def PRG_bufaddr, PRG_paddr
    .def PRG_length, PARMS
    .def SEG_ST,SEG_END,PROTECT
*****
VARS: .usect "PRG_data",16;This is an uninitialized data *
        ;section required by the standard *
        ;flash algos for temporary *
        ;variables. Pointers to this *
        ;space are hardcoded in SVAR20.H, *
        ;and variables are init'd at *
        ;run time. *
*****
PARMS: .usect "PRG_parm",10;This is an uninitialized data *
        ;section used for temporary *
        ;variables and for passing *
        ;parameters to the flash *
        ;algorithms. *
*****
PROTECT .set PARMS ;Segment enable bits. *
*****
**** Parameters needed for Programming algorithm. ****
*****
PRG_bufaddr .set PARMS+1 ;Addr of buffer for pgm data *
PRG_paddr .set PARMS+2 ;First flash addr to program *
PRG_length .set PARMS+3 ;Length of block to program *
*****
** Parameters needed for CLEAR, ERASE, and FLW algorithms. *
*****
SEG_ST .set PARMS+4 ;Segment start address. *
SEG_END .set PARMS+5 ;Segment end address. *
*****
**** Other misc variables. ****
*****
ERS_COUNT .set PARMS+6 ;Used for erase fail count. *
SV_AR1 .set PARMS+7 ;Used to save AR1. *
*****
.sect "PRG_text"
*****
* function erase(PROTECT,SEG_ST,SEG_END) *
* Status is returned in the accumulator. *
* 0 = Fail,1 = Pass *
*****
* This function performs the clear and erase operation *
* on the 'F2XX flash. If the erase operation fails, the *
* flash-write operation is used to try to recover from *
* depletion. If the array recovers, the entire process *
* (clr+ers+flw) is repeated a maximum of 10 times. The *
* return value indicates the status. If this function *

```



```

* passes, the flash is ready to be reprogrammed. The      *
* operations are performed on the segments of the flash *
* module described by the parameter list:                *
*   1)PROTECT-defines which flash segments to protect.*
*   2)SEG_ST -start address of segment to be erased.    *
*   3)SEG_END-end address of segment to be erased.      *
* To erase flash0 use erase(0xff00,0x0000,0x3fff).      *
* To erase flash1 use erase(0xff00,0x4000,0x7fff).      *
*****
* CAUTION: Erasing individual segments is not allowed.  *
* The PROTECT parameter should always be set to        *
* enable all segments, and SEG_ST and SEG_END          *
* should be set to the end and start address of        *
* the array to be erased.                              *
*****
_erase:
ERS_PARAMS      .set 3
AR_STACK        .set ar1
AR_PROTECT      .set ar2
AR_SEG_ST       .set ar3
AR_SEG_END      .set ar4

;Begin C Preprocessing
POPD    *+      ;pop return address, push on software stack
sar     ar0,*+  ;save FP
sar     ar6,*   ;save ar6
sbrk    #3
        ;get arguments and place them properly - take them from
        ;the software stack and place them into their correct
        ;positions
lar     AR_PROTECT,*-
lar     AR_SEG_ST,*-
lar     AR_SEG_END,*-
adrk   #ERS_PARAMS+4 ;ar1 = next empty point on stack (SP)
;End C Preprocessing
LDP     #PARMS
SAR     AR1,SV_AR1 ;Save AR1.
SPLK    #0,ERS_COUNT ;Set erase fail count to 0.
SPLK    #0,ERROR     ;Set algo error flag to 0 (no errors).
*****Put parameters where they belong.*****
SAR     AR_PROTECT,PROTECT
SAR     AR_SEG_ST,SEG_ST
SAR     AR_SEG_END,SEG_END
*****Next Setup to clear flash *****
ers_loop:
CALL    GCLR          ;Clear flash.
LACL    ERROR         ;Check for CLEAR/ERASE error
BCND    ers_error,neq;If error, then hard fail.
*****Next Setup to erase flash *****
CALL    GERS          ;Erase flash.
LACL    ERROR         ;Check for CLEAR/ERASE error
BCND    depletion,neq;If error, try Flash-write.
LACL    #1            ;Else, no errors erasing.
B       ers_done      ;Restore registers and return.
depletion:
LACL    ERS_COUNT     ;Get erase fail count.

```

```

        ADD    #1           ;Increment fail count.
        SACL   ERS_COUNT   ;Save new count.
        SUB    #10        ;CHECK for max of 10.
        BCND   ers_error,GT ;If ers_cout>10 then hard fail.
        CALL   FLWS       ;Else, try to recover from depletion.
        LACL   ERROR      ;Check for FLASH-WRITE error.
        BCND   ers_error,neq ;If couldn't recover, then hard fail.
        B      ers_loop    ;Else, try erase again.
ers_error:
        LACL   #0         ;Error while erasing.
ers_done:
        LAR    AR1,SV_AR1 ;Restore AR1.
        CLRC   OVM        ;Disable overflow.
*****
;Begin C Post Processing
        mar *,ar1
        sbrk #1
        lar   ar6,*-      ;save FP
        lar   ar0,*-      ;save ar6
        pshd *            ;pop return address, push on s/w stack
;End C Post Processing
        ret
*****END of _erase*****

*****
*   function  program(PROTECT,PRG_bufaddr,PRG_paddr,      *
*               PRG_length)                             *
*   Status will be returned in the accumulator.         *
*   0 = Fail, 1 = Pass                                  *
*****
*   This function performs the program operation on the *
*   'F2XX flash. The values to be programmed will be read *
*   from a buffer in data memory. The function can program *
*   one to n words of flash in a single call; restricted *
*   only by the data buffer size. If the function passes, *
*   the flash was programmed correctly. The function is *
*   controlled by the following parameter list:         *
*   1)PROTECT    -flash segments to protect.           *
*   2)PRG_bufaddr-Start address of program buffer in *
*               data memory.                            *
*   3)PRG_paddr  -Start address of flash locations to *
*               be programmed.                          *
*   4)PRG_length -Number of words to be programmed.   *
*
*   To program 20 words of flash1 starting at address *
*   0x4020, from a buffer at 0x0800@data use this:    *
*   program(0xff00,0x0800,0x4020,20).                 *
*****
_program:
PRG_PARAMS    .set 4
AR_STACK      .set ar1
; **Parameters to be popped from s/w stack.
AR_PROTECT    .set ar2
AR_bufaddr    .set ar3
AR_paddr      .set ar4
AR_length     .set ar5

```

```

;Begin C Preprocessing
  POPD  *+          ; pop return address, push on s/w stack
  sarar0,*+         ; save FP
  sarar6,*         ; save ar6
  sbrk #3
  ; Local variables (and parameters) are set up as follows:
  ;
  ;get arguments and place them properly - take them from
  ;the software stack and place them into their correct
  ;positions
  lar AR_PROTECT,*-
  lar AR_bufaddr,*-
  lar AR_paddr,*-
  lar AR_length,*-
  adrk #PRG_PARAMS+4 ; ar1 = next empty point on stack (SP)
; End C Preprocessing
  LDP   #PARMS
  SAR   AR1,SV_AR1   ;Save AR1.
  SPLK  #0,ERROR     ;Set algo error flag to 0
                          ;(no errors).
*****Put parameters where they belong.*****
  SAR   AR_PROTECT,PROTECT
  SAR   AR_bufaddr,PRG_bufaddr
  SAR   AR_paddr,PRG_paddr
  SAR   AR_length,PRG_length
*****Next, program flash *****
  CALL  GPGMJ        ;Program flash from buffer.
  LACL  ERROR        ;Check for program error.
  BCND  prg_error,neq ;If error then clear ACC.
  LACL  #1           ;Else, No errors programming.
  B     prg_done

prg_error:
  LACL  #0           ;Error while programming.
prg_done:
  LAR   AR1,SV_AR1   ;Restore AR1.
  CLRC  OVM          ;Disable overflow.
*****
;Begin C Post Processing
  mar  *,ar1
  sbrk #1
  lar  ar6,*-        ;save FP
  lar  ar0,*-        ;save ar6
  pshd *            ;pop return address, push on s/w stack
;End C Post Processing
  ret
*****END of _program*****

```

A.3 Sample Assembly Code to Erase and Reprogram the TMS320F206

The algorithm files can be used from assembly in a straightforward manner. In general, the algorithms can reside anywhere in program space. However, the algorithms cannot be executed from the flash module that is being modified, and the algorithms must execute with zero wait states. The assembly code and linker command file in this section provide a working example for the 'F206. In this example, the algorithms reside in SARAM, and flash1 is erased and reprogrammed.

A.3.1 Assembly Code for TMS320F206

```

*****
*  Filename: ASMEXAMP.ASM                               *
*  Description:                                         *
*  This file contains an example of how to erase       *
*  and program the TMS320F206 flash from assembly     *
*  code using the standard flash algorithm modules.   *
*  The example erases one of the 'F206 flash         *
*  modules, then programs the first three words.     *
*  Since the standard flash algorithms are actually   *
*  used to perform the various flash operations,     *
*  they must be combined with this code at           *
*  link time.                                         *
*                                                     *
*  03/20/98 Updated for inclusion in flash           *
*  technical reference.                               *
*****
        .title "***Example of Using 'F2XX Flash Algorithms**"
; **Variables included from flash algorithms.
        .include "svar20.h"      ;Variable declarations
        .ref  GCLR               ;References clear algo.
        .ref  GPGMJ             ;References program algo.
        .ref  GERS               ;References erase algo.
        .ref  FLWS              ;References Flash-write algo.
; **Parameters used by flash algorithms.
        .def  PRG_bufaddr, PRG_paddr
        .def  PRG_length, PARMS
        .def  SEG_ST, SEG_END, PROTECT
*****
VARS:  .usect "PRG_data", 16    ;This is an uninitialized *
                                   ;data section required by *
                                   ;the standard flash algos *
                                   ;for temporary variables. *
                                   ;Pointers to this space *
                                   ;are hardcoded in SVAR20.H, *
                                   ;and variables are *
                                   ;init'd at run time. *
*****
PARMS: .usect "PRG_parm", 10   ;This is an uninitialized *

```

```

;data section used for      *
;temporary variables, and  *
;for passing parameters    *
;to the flash algorithms.  *
*****
PROTECT .set  PARMS      ;Segment enable bits.      *
*****
***Parameters needed for Programming algorithm.    ***
*****
PRG_bufaddr .set  PARMS+1 ;Address of buffer for      *
;program data.                                     *
PRG_paddr   .set  PARMS+2 ;First flash address to    *
;program.                                          *
PRG_length  .set  PARMS+3 ;Length of block to program.*
*****
* Parameters needed for CLEAR, ERASE, and FLW algorithms.
*
*****
SEG_ST      .set  PARMS+4 ;Segment start address.    *
SEG_END     .set  PARMS+5 ;Segment end address.      *
*****
****          Other misc variables.                ****
*****
ERS_COUNT   .set  PARMS+6 ;Used for erase fail count. *
*****
.text
*****
** First, erase flash1 by invoking the clear and erase *
** algorithms.                                         *
** Note: three parameters must be initialized before  *
** calling the algorithms.                             *
*****
        LDP    #PARMS
        SPLK   #0,ERS_COUNT ;Set erase fail count to 0.
*****Put parameters where they belong.*****
        SPLK   #0ff00h,PROTECT
        SPLK   #04000h,SEG_ST
        SPLK   #07FFFh,SEG_END
*****First clear flash *****
ers_loop:
        CALL   GCLR          ;Clear flash.
        LACL   ERROR        ;Check for CLEAR error
        BCND   ers_error,neq ;If error, then hard fail.
*****Next erase flash *****
        CALL   GERS          ;Erase flash.
        LACL   ERROR        ;Check for CLEAR error
        BCND   depletion,neq ;If error, then try
;flash-write.
        B      ers_done     ;Else, no errors erasing.
depletion:
        LACL   ERS_COUNT    ;Get erase fail count.
        ADD   #1           ;Increment fail count.
        SACL   ERS_COUNT    ;Save new count.

```

```

SUB #10                ;CHECK for max of 10.
BCND  ers_error,GT    ;If ers_cout>10 then hard
                        ;fail.
CALL  FLWS            ;Else, try to recover from
                        ;depletion.
LACL  ERROR           ;Check for FLASH-WRITE error.
BCND  ers_error,neq   ;If couldn't recover, then
                        ;hard fail.
B     ers_loop        ;Else, try erase again.

ers_error:
*****
** If here, then an unrecoverable error has occurred **
** during erase. In an actual application, the system**
** takes some action to indicate that service is     **
** required.                                          **
*****
B     ers_error       ;Error while erasing.

ers_done:
*****
** If here, then flash is erased and ready to be     **
** reprogrammed. This is a good place in the example **
** to set a breakpoint so that erasure can be       **
** verified (i.e., all flash bits should be 1).     **
*****

*****
** At this point, an actual application fills a buffer **
** with the data to be programmed. To simulate this in **
** the example, three SARAM locations are initialized. **
*****
LAR   AR1, #0c00h;Using last 3K of SARAM as
                        ;buffer.
MAR   *,AR1
SPLK  #0AAAAh,*+      ;Use dummy data for buffer.
SPLK  #05555h,*+
SPLK  #0AAAAh,*

*****
** Now that the data to be programmed is ready, the   **
** programming algorithm is invoked. Note that four   **
** parameters must be initialized before calling the  **
** algorithm.                                          **
*****
LDP  #PARMS
*****Put parameters where they belong.*****
splk  #0ff00h,PROTECT
splk  #0c00h,PRG_bufaddr
splk  #04000h,PRG_paddr
splk  #3,PRG_length
*****Next program flash *****
CALL  GPGMJ           ;Program flash from buffer.
LACL  ERROR           ;Check for program error.
BCND  prg_error,neq   ;If error then clear ACC.
B     prg_done        ;Else, No errors programming.

```

```

prg_error:
*****
** If here, then an error has occurred during          **
** programming. In an actual application, the system  **
** takes some action to indicate that service is     **
** required.                                          **
*****
        B        prg_error        ;Error while programming.

prg_done:
*****
** If here, then flash has been successfully programmed.**
*****
        B        prg_done        ;Done programming.

```

A.3.2 Linker Command File for TMS320F206 Sample Assembly Code

```

/*****/
/* Filename: ASMEXAMP.CMD */
/* Description: Linker command file for 'F206 example of on-chip */
/* flash programming from assembly. This command file links the example to addr */
/* 0x8000 of the on-chip SARAM so that the debugger can be used to set */
/* breakpoints. Another benefit of linking the example to SARAM is that the */
/* code can be modified to operate on either flash module0, or module1, or */
/* both. */
/* Notes: */
/* 1. This example expects the 'F206 SARAM to be mapped in both data space */
/* and program space (DON=PON=1). */
/* 2. The object modules for the standard flash algos are expected to be in */
/* a subdirectory (ALGOS) of the path of this file. */
/*****/
/* Rev1.0 3/98 RDP */
/*****/

/*****Command Line Options*****/
-e .text
-o asmexamp.out
-m asmexamp.map

/*****Input Files*****/
asmexamp.obj /*User assembly code that calls flash algos. */
algos\spgm20.obj /*Standard Programming algorithm. */
algos\sclr20.obj /*Standard Clear algorithm. */
algos\sera20.obj /*Standard Erase algorithm. */
algos\sflw20.obj /*Standard Flash-write algorithm. */
algos\sutils20.obj /*Subroutines used by standard algos. */

/*****Memory Map*****/
MEMORY
{
PAGE 0: /* PM - Program memory */

FLASH0: origin = 0x0000, length = 0x3fff
FLASH1: origin = 0x4000, length = 0x3fff
PSARAM: origin = 0x8000, length = 0x400 /*Use 1K of SARAM for PROGRAM */
B0: origin = 0xff00, length = 0x1ff

```

```

PAGE 1:  /* DM - Data memory */

BLK_B2: origin = 0x60,length = 0x20          /*BLOCK B2                */
DSARAM: origin = 0xc00, length = 0xc00      /*Use 3K of SARAM for data DON=1 */
EX1_DM: origin = 0x4000, length = 0x4000    /*External data RAM          */
B1: origin = 0x300, length = 0x1ff         /*B1 Ram (Used for algo vars )  */
}

/*****Section Allocation*****/
SECTIONS
{
    .text : {} > PSARAM PAGE 0 /* asmexamp.asm */

    /*All these sections are for flash programming.*/
    fl_prg : {} > PSARAM PAGE 0 /*Programming Algorithm*****/
    fl_clr : {} > PSARAM PAGE 0 /*****Clear Algorithm*****/
    fl_ers : {} > PSARAM PAGE 0 /*****Erase Algorithm*****/
    fl_wrt : {} > PSARAM PAGE 0 /*****Flash-write Algorithm*****/
    DLY : {} > PSARAM PAGE 0 /*****Delay Subroutine*****/
    REG : {} > PSARAM PAGE 0 /*****Regs Subroutine*****/
    ARY : {} > PSARAM PAGE 0 /*****Array Subroutine*****/
    PRG_data : {} > B1 PAGE 1 /*Reserved in asmexamp.asm **/
    /*for flash algo variables.**/
    PRG_parm : {} > B1 PAGE 1 /*Reserved in asmexamp.asm **/
    /*for param passing to algos*/
    /*End of sections for flash programming. */
}

```


A.4 Sample C Code to Erase and Reprogram the TMS320F206

Because the algorithm implementations do not follow the C-calling convention of the 'C2000 C environment, they cannot be used directly from C. The assembly code of section A.2, *C-Callable Interface to Flash Algorithms*, is provided as a C-callable interface to the programming algorithms. The following C source file and linker command file provide a working example for the 'F206. In this example, the algorithms reside in the on-chip SARAM, and either flash0 or flash1 can be reprogrammed. The code can be relocated anywhere in program space, with the exceptions described in section A.3, *Using the Algorithms With Assembly Code*.

A.4.1 C Code That Calls the Interface to Flash Algorithms for TMS320F206

```

/*****
/* Filename: sample.c
/* Description: This is an example of how to
/* program the 'F2XX flash from C code.
/* The C-callable interface for the standard
/* flash algorithms is used. This interface is
/* defined in the file <flash.asm>, as two
/* C-callable functions: erase(), and program()
/* At link time, this example must be combined
/* with the code in <flash.asm> as well as with
/* the object modules for the standard algos.
/*****
/* This example is set up for the TMS320F206,
/* and uses the SARAM as a buffer for programming
/* data. The code first erases module1,
/* then programs the first three locations.
/*****
/* Rev1.0 10/97 RDP */
/*****
extern int erase(); /* Declare external func for flash erase. */
extern int program(); /* Declare external func for flash programming. */
main()
{
    int *a;
    if (erase(0xff00,0x4000,0x7fff))
    { /*Flash is erased, now let's program it.*/
        /* Init program buffer. */
        a=(int *)0xC00; /*Use last 3K of SARAM for data buffer*/
        a[0]=0x7A80;
        a[1]=0x0FDF;
        a[2]=0x7A80;

        /*Program the flash from the buffer*/
        if (program(0xff00,0xc00,0x4000,0x3))
        { /*Flash programmed ok.*/
            while(1){} /*Spin here forever*/
        }
        else

```

```

        { /*Flash fails programming, EXIT*/
          while(1){} /*Spin here forever*/
        }
      }
    else
    { /*Flash fails erase, EXIT*/
      while(1){} /*Spin here forever*/
    }
  }
}

```

A.4.2 Linker Command File for TMS320F206 Sample C Code

```

/*****
/* Filename: F206_SA.CMD
/* Description: Linker command file for 'F206 example of on-chip flash
/* programming from C code. This command file links the
/* example to addr 0x8000 of the on-chip SARAM so that
/* the debugger can be used to set breakpoints. Another
/* benefit of linking the example to SARAM is that the
/* C code can be modified to operate on either flash
/* module0, or module1, or both.
/* Notes:
/* 1. This example expects the 'F206 SARAM to be
/* mapped in both data space and program space
/* (DON=PON=1).
/* 2. The object modules for the standard flash algos
/* are expected to be in a subdirectory (ALGOS) of
/* the path of this file.
*****/
/* Rev1.0 10/97 RDP */
*****/

/*****Command Line Options*****/
-cr /*Use Ram init model.
-heap 0x0 /*No heap needed for this example.
-stack 0x96 /*150-word stack is enough for this example.
-x /*Force rereading of libraries.
-l c:\dsptools\rts2xx.lib
-o sample_S.out
-m sample_S.map

/*****Input Files*****/
sample.obj /*User C code with calls to erase() and program() */
flash.obj /*C-callable interface to standard algorithms.
algos\spgm20.obj /*Standard Programming algorithms.
algos\sclr20.obj /*Standard Clear algorithm.
algos\sera20.obj /*Standard Erase algorithm.
algos\sflw20.obj /*Standard Flash-write algorithm.
algos\sutils20.obj /*Subroutines used by standard algorithms.

/*****Memory Map*****/
MEMORY
{
PAGE 0: /* PM - Program memory */

```

```

FLASH0:  origin = 0x0000,  length = 0x3fff
FLASH1:  origin = 0x4000,  length = 0x3fff
PSARAM:  origin = 0x8000,  length = 0x400 /*Use 1K of SARAM for PROGRAM*/
B0:      origin = 0xff00,  length = 0x1ff

PAGE 1: /* DM - Data memory */

BLK_B2:  origin = 0x60,    length = 0x20 /*BLOCK B2 */
DSARAM:  origin = 0xc00,   length = 0xC00 /*Use 3K of SARAM for data */
/*DON=1*/

EX1_DM:  origin = 0x4000,  length = 0x4000 /*External data RAM */
B1:      origin = 0x300,   length = 0x1ff /*B1 RAM (Used for algo vars)*/
}

/*****Section Allocation*****/
SECTIONS
{
    .text      :  {} > PSARAM PAGE 0    /* sample.c */

    /*All these sections are for flash programming.*/
    PRG_text   :  {} > PSARAM PAGE 0    /**erase() and program()*****/
    /*****from flash.asm file*****/

    fl_prg     :  {} > PSARAM PAGE 0    /**Programming Algorithm*****/
    fl_clr     :  {} > PSARAM PAGE 0    /******Clear Algorithm*****/
    fl_ers     :  {} > PSARAM PAGE 0    /******Erase Algorithm*****/
    fl_wrt     :  {} > PSARAM PAGE 0    /******Flash-write Algorithm*****/
    DLY        :  {} > PSARAM PAGE 0    /******Delay Subroutine*****/
    REG        :  {} > PSARAM PAGE 0    /******Regs Subroutine*****/
    ARY        :  {} > PSARAM PAGE 0    /******Array Subroutine*****/
    PRG_data   :  {} > B1 PAGE 1        /*Reserved in flash.asm for**/
    /*****flash algo variables.*****/
    PRG_parm   :  {} > B1 PAGE 1        /*Reserved in flash.asm for**/
    /*****parameter passing to algos*****/

    /*End of sections for flash programming. */

    .bss       :  {} > B1 PAGE 1
    .cinit     :  {} > B1 PAGE 1
    .const     :  {} > B1 PAGE 1
    .data      :  {} > B1 PAGE 1
    .stack     :  {} > B1 PAGE 1    /*C stack. */
}

```

A.5 Sample Assembly Code to Erase and Reprogram the TMS320F240

The algorithm files can be used from assembly in a straightforward manner. In general, the algorithms can reside anywhere in program space. However, the algorithms cannot be executed from the flash module that is being modified, and the algorithms must execute with zero wait states. The assembly code and linker command file in this section provide a working example for the 'F240.

Note:

This is not an actual application example since a boot mechanism is required to load the external SRAM on powerup. This example uses the 'C2xx C-source Debugger to download the code to the external SRAM. In addition, no reset or interrupt vectors are initialized.

The system requirements are F240 EVM or target board with external program space SRAM located at 0x8000 and a minimum of 1K words.

A.5.1 Assembly Code for TMS320F240

```
*****
*   Filename: ASMEXA24.ASM                               *
*   Description:                                         *
*   This file contains an example of how to erase       *
*   and program the TMS320F240 flash from assembly     *
*   code using the standard flash algorithm modules.   *
*   The example erases the 'F240 flash                 *
*   modules, then programs the first three words.     *
*   Since the standard flash algorithms are actually   *
*   used to perform the various flash operations,     *
*   they must be combined with this code at           *
*   link time.                                         *
*                                                       *
*   03/25/98   Updated for inclusion in flash         *
*               technical reference.                   *
*****
               .title "***Example of Using 'F2XX Flash Algorithms**"
```

```

**Variables included from flash algorithms.
    .include "svar20.h" ;Variable declarations
    .ref GCLR ;References clear algo.
    .ref GPGMJ ;References program algo.
    .ref GERS ;References erase algo.
    .ref FLWS ;References flash-write algo.
**Parameters used by flash algorithms.
    .def PRG_bufaddr, PRG_paddr
    .def PRG_length, PARMS
    .def SEG_ST,SEG_END,PROTECT
**F240 Register definitions
RTICR .set 07027h ;RTI Control Register
WDCR .set 07029h ;WD Control Register
CKCR0 .set 0702Bh ;Clock Control Register 0
CKCR1 .set 0702Dh ;Clock Control Register 1
SYSSR .set 0701Ah ;System Module Status Register
DP_PFI .set 224 ;page 1 of peripheral file
; (7000h/80h)

*****
VARS: .usect "PRG_data",16 ;This is an uninitialized data *
;section required by the standard *
;flash algos for temporary *
;variables. Pointers to this *
;space are hardcoded in SVAR20.H, *
;and variables are init'd at *
;run time. *
*****
PARMS: .usect "PRG_parm",10 ;This is an uninitialized data *
;section that is used for *
;temporary variables and for *
;passing parameters to the flash *
;algorithms. *
*****
PROTECT .set PARMS ;Segment enable bits. *
*****
**** Parameters needed for Programming algorithm. ****
*****
PRG_bufaddr .set PARMS+1 ;Addr of buffer for pgm data. *
PRG_paddr .set PARMS+2 ;1st flash addr to program. *
PRG_length .set PARMS+3 ;Length of block to program. *
*****
****Parameters needed for CLEAR, ERASE, and FLW algorithms. ****
*****
SEG_ST .set PARMS+4 ;Segment start address. *
SEG_END .set PARMS+5 ;Segment end address. *
*****
**** Other misc variables. ****
*****
ERS_COUNT .set PARMS+6 ;Used for erase fail count. *
*****
.text
*****
** First, initialize the key F240 registers for use with *
** the EVM. *
*****

```

```

F240INIT: ;Set Data Page pointer to page 1 of the
          ;peripheral frame
          LDP #DP_PF1          ;Page DP_PF1 includes WET through*
                                ;EINT frames
          ;initialize WDT registers
          SPLK #06Fh,WDCR      ;clear WDFLAG, Disable WDT
                                ;(if Vpp=5V), set WDT
                                ;for 1 second overflow (max)
          SPLK #07h, RTICR     ;clear RTI Flag,
                                ;set RTI for 1 second overflow
                                ;(max)
          ;EVM 10-MHz oscillator settings.
          ;(XTAL2 open, OSCBYP_=GND)
          SPLK #00B1h,CKCR1    ;CLKIN(OSC)=10MHZ,
                                ;Mult by 2, Div by 1.
          SPLK #00C3h,CKCR0    ;CLKMD=PLL Enable,SYSCLK=CPUCLK/2

          ;Clear reset flag bits in SYSSR
          ;(PORRST, PLLRST, ILLRST, SWRST, WDRST)
          LACL SYSSR           ;ACCL <= SYSSR
          AND #00FFh          ;Clear upper 8 bits of SYSSR
          SACL SYSSR          ;Load new value into SYSSR

*****
** First, erase flash1 by invoking the clear and erase **
** algorithms. **
** Note: Three parameters must be initialized before **
** calling the algorithms. **
*****
          LDP #PARMS
          SPLK #0,ERS_COUNT    ;Set erase fail count to 0.
*****Put parameters where they belong.*****
          SPLK #0ff00h,PROTECT
          SPLK #00000h,SEG_ST
          SPLK #03FFFh,SEG_END
*****First, clear flash *****

ers_loop:
          CALL GCLR            ;Clear flash.
          LACL ERROR          ;Check for CLEAR/ERASE error
clrerr:   BCND ers_error,neq  ;If error, then hard fail.
*****Next erase flash *****
          CALL GERS            ;Erase flash.
          LACL ERROR          ;Check for CLEAR/ERASE error
          BCND depletion,neq  ;If error, then try Flash-write.
          B ers_done          ;Else, no errors erasing.

```

```

depletion:
    LACL  ERS_COUNT      ;Get erase fail count.
    ADD   #1             ;Increment fail count.
    SACL  ERS_COUNT      ;Save new count.
    SUB   #10           ;CHECK for max of 10.
    BCND  ers_error,GT  ;If ers_cout>10 then hard fail.
    CALL  FLWS          ;Else, try to recover from
                        ;depletion.

    LACL  ERROR         ;Check for FLASH-WRITE error.
    BCND  ers_error,neq ;If couldn't recover, then hard
                        ;fail.

    B     ers_loop      ;Else, Try erase again.

ers_error:
*****
** If here, then an unrecoverable error occurred during      **
** erase.                                                     **
** In an actual application, the system takes some action   **
** to indicate that service is required.                    **
*****
    B     ers_error     ;Error while erasing.

ers_done:
*****
** If here, then flash is erased and ready to be           **
** reprogrammed.                                           **
** This is a good place in the example to set a            **
** breakpoint so that erasure can be verified (i.e.,       **
** all flash bits should be 1).                             **
*****

*****
** At this point, an actual application fills a buffer with **
** the data to be programmed. To simulate this in the     **
** example, three DARAM locations are initialized.         **
*****
    LAR   AR1, #0380h   ;Using last 128 words of B1 DARAM
                        ;as buffer.

    MAR   *,AR1
    SPLK  #0AAAAh,*+   ;Use dummy data for buffer.
    SPLK  #0555h,*+
    SPLK  #0AAAAh,*

```

```
*****
** Now that the data to be programmed is ready, the      **
** programming algorithm is invoked. Note: Four parameters **
** must be initialized before calling the algorithm.      **
*****
    LDP    #PARMS
*****Put parameters where they belong.*****
    splk  #0ff00h,PROTECT
    splk  #0380h,PRG_bufaddr
    splk  #00000h,PRG_paddr
    splk  #3,PRG_length
*****Next, program flash*****
    CALL  GPGMJ          ;Program flash from buffer.
    LACL  ERROR          ;Check for program error.
    BCND  prg_error,neq ;If error then clear ACC.
    B     prg_done      ;Else, No errors programming.

prg_error:
*****
** If here, then an error occurred during programming.  **
** In an actual application, the system takes some     **
** action to indicate that service is required.       **
*****
    B     prg_error     ;Error while programming.

prg_done:
*****
** If here, then flash has been successfully programmed.*
*****
    B     prg_done     ;Done programming.
```


A.5.2 Linker Command File for TMS320F240 Sample Assembly Code

```

/*****
/* Filename: ASMEXA24.CMD
/* Description: Linker command file for 'F240 example of
/* on-chip flash programming from assembly. This command
/* file links the example to addr 0x8000 of the off-chip
/* pgm RAM, so that the debugger can be used to set
/* breakpoints.
/* Notes:
/* 1. The object modules for the standard flash
/* algos are expected to be in a subdirectory
/* (ALGOS) of the path of this file.
/*****
/* Rev1.0 3/98 JGC */
/*****

/*****Command Line Options*****/
-e .text
-o asmexa24.out
-m asmexa24.map

/*****Input Files*****/
asmexa24.obj /*User assembly code that calls flash algos. */
algos\spgm20.obj /*Standard Programming algorithm. */
algos\sclr20.obj /*Standard Clear algorithm. */
algos\sera20.obj /*Standard Erase algorithm. */
algos\sflw20.obj /*Standard Flash-write algorithm. */
algos\sutils20.obj /*Subroutines used by standard algorithms. */

/*****Memory Map*****/
MEMORY
{
PAGE 0: /* PM - Program memory */

FLASH0: origin = 0x0000, length = 0x4000
EXTRAM: origin = 0x8000, length = 0x400 /*Use 1K of Ext. RAM for PROGRAM*/
B0PGM: origin = 0xfe00, length = 0x100

PAGE 1: /* DM - Data memory */

BLK_B2: origin = 0x60, length = 0x20 /* BLOCK B2*/
EX1_DM: origin = 0x8000, length = 0x4000 /* External data RAM */
B0: origin = 0x200, length = 0x100 /* B0 Ram (Used for temp data )*/
B1: origin = 0x300, length = 0x100 /* B1 Ram (Used for algo vars )*/
}

/*****Section Allocation*****/
SECTIONS
{
.text :{ } > EXTRAM PAGE 0 /* asmexa24.asm */

```

```
/*All these sections are for flash programming.*/
fl_prg      : {} > EXTRAM    PAGE 0 /**Programming Algorithm***/
fl_clr      : {} > EXTRAM    PAGE 0 /******Clear Algorithm*****/
fl_ers      : {} > EXTRAM    PAGE 0 /******Erase Algorithm*****/
fl_wrt      : {} > EXTRAM    PAGE 0 /****Flash-write Algorithm***/
DLY         : {} > EXTRAM    PAGE 0 /******Delay Subroutine*****/
REG         : {} > EXTRAM    PAGE 0 /******Regs Subroutine*****/
ARY         : {} > EXTRAM    PAGE 0 /******Array Subroutine*****/
PRG_data    : {} > B1        PAGE 1 /*Reserved in asmexamp.asm */
                                     /*for flash algo variables.*/
PRG_parm    : {} > B1        PAGE 1 /*Reserved in asmexamp.asm */
                                     /*for param passing to algos*/
/*End of sections for flash programming.*/
}
```

A.6 Using the Algorithms With C Code to Erase and Reprogram the 'F240

Because the algorithm implementations do not follow the C-calling convention of the 'C2000 C environment, they cannot be used directly from C. The assembly code of section A.2, *C-Callable Interface to Flash Algorithms*, is provided as a C-callable interface to the programming algorithms. The C source file and linker command file provide a working example for the 'F240.

In this example, the algorithms reside in external SRAM. The code can be relocated anywhere in program space, with the exceptions described in section A.3, *Using the Algorithms With Assembly Code*.

Note:

This is not an actual application example since a boot mechanism is required to load the external SRAM on powerup. This example uses the 'C2xx C-source Debugger to download the code to the external SRAM. In addition, no reset or interrupt vectors are initialized.

The system requirements are F240 EVM or target board with external program space SRAM located at 0x8000 and a minimum of 1K words.

A.6.1 C Code That Calls the Interface to Flash Algorithms for TMS320F240

```

/*****
/* Filename: sample24.c                               */
/* Description: This is an example of how to          */
/* program the 'F2XX flash from C code.              */
/* The C-callable interface for the standard         */
/* flash algorithms is used. This interface is       */
/* defined in the file <flash.asm>, as two           */
/* C-callable functions: erase(), and program()      */
/* At link time, this example must be combined     */
/* with the code in <flash.asm> as well as with     */
/* the object modules for the standard algos.       */
/*****
/* This example is setup for the TMS320F240,        */
/* and uses the B1 DARAM as a buffer for program-   */
/* -ming data. The code first clears, erases,      */
/* then programs the first three locations.         */
/*****
/* Rev1.0                                           03/98 JGC  */
/*****

```

```

extern int    erase();      /* Declare external func for flash erase. */
extern int    program();    /* Declare external func for flash programming */
extern c240init();         /* Declare external func for C240 register init'l'n */
extern wdtoff();          /* Declare external func for wdt disable */
main()
{
    int *a;
    asm("    CLRC CNF ");    /* map B0 to data space */
    c240init();             /* initialize key '240 registers */
    wdtoff();              /* disable WD timer (works when VCCP=5v) */
    if (erase(0xff00,0x0000,0x3fff))
    { /*Flash is erased, now let's program it.*/

        /* Init program buffer. */
        a=(int *)0x200;     /*Use last 128 words of B1 DARAM for data buffer*/
        a[0]=0x7A80;
        a[1]=0x0FDF;
        a[2]=0x7A80;

        /*Program the flash from the buffer*/
        if (program(0xff00,0x200,0x0000,0x3))
        { /*Flash programmed ok.*/
            while(1){} /*Spin here forever*/
        }
        else
        { /*Flash fails programming, EXIT*/
            while(1){} /*Spin here forever*/
        }
    }
    else
    { /*Flash fails erase, EXIT*/
        while(1){} /*Spin here forever*/
    }
}

```

A.6.2 Linker Command File for TMS320F240 Sample C Code

```

/*****
/* Filename: F240_EXT.CMD */
/* Description: Linker command file for 'F240 example of on-chip flash */
/* programming from C-code. This command file links the */
/* example to addr 0x8000 of the offchip SRAM, so that */
/* the debugger can be used to set breakpoints. */
/* Notes: */
/* 1. The object modules for the standard flash algos */
/* are expected to be in a subdirectory (ALGOS) of */
/* the path of this file. */
*****/
/* Rev1.0 03/98 JGC */
/*****

```

```

/*****Command Line Options*****/
-cr                /*Use Ram init model.                */
-heap 0x0          /*No heap needed for this example.                */
-stack 0x96        /*150 word stack is enough for this example.      */
-x                /*Force re-reading of libraries.                */
-l c:\dsptools\fix\rts2xx.lib
-o sample24.out
-m sample24.map

/*****Input Files*****/
sample24.obj       /*User C-code with calls to erase() and program() */
c240init.obj       /*C-callabe asm function to init '240 regs        */
wdtoff.obj        /*C-callable asm function to disable the wdt      */
flash.obj         /*C-callable interface to standard algorithms.    */
algos\spgm20.obj  /*Standard Programming algorithms.                */
algos\sclr20.obj  /*Standard Clear algorithm.                       */
algos\sera20.obj  /*Standard Erase algorithm.                       */
algos\sflw20.obj  /*Standard Flash-write algorithm.                */
algos\sutils20.obj /*Subroutines used by standard algorithms.        */

/*****Memory Map*****/
MEMORY
{
PAGE 0: /* PM - Program memory */

    FLASH0: origin = 0x0000, length = 0x4000
    EXTRAM: origin = 0x8000, length = 0x400 /*Use 1K of EXT SRAM for PROGRAM*/
    B0: origin = 0xfe00, length = 0x100

PAGE 1: /* DM - Data memory */

    BLK_B2: origin = 0x60, length = 0x20 /*BLOCK B2 */
    DSRAM: origin = 0x8000, length = 0x4000 /*External data RAM */
    BODAT: origin = 0x200, length = 0x100 /*B0 RAM */
    /*(Used for pgm data buffer)*/
    B1: origin = 0x300, length = 0x100 /* B1 RAM (Used for algo vars)*/
}

/*****Section Allocation*****/
SECTIONS
{
    .text :{} > EXTRAM PAGE 0 /* sample.c */
    /*All these sections are for flash programming.*/
    PRG_text : {} > EXTRAM PAGE 0 /**erase() and program()*****/
    /******from flash.asm file*****/
    fl_prg : {} > EXTRAM PAGE 0 /**Programming Algorithm*****/
    fl_clr : {} > EXTRAM PAGE 0 /**Clear Algorithm*****/
    fl_ers : {} > EXTRAM PAGE 0 /**Erase Algorithm*****/
    fl_wrt : {} > EXTRAM PAGE 0 /**Flash-write Algorithm***/
    DLY : {} > EXTRAM PAGE 0 /**Delay Subroutine*****/
    REG : {} > EXTRAM PAGE 0 /**Regs Subroutine*****/
    ARY : {} > EXTRAM PAGE 0 /**Array Subroutine*****/
    PRG_data : {} > B1 PAGE 1 /*Reserved in flash.asm for**/
    /***flash algo variables.***/
    PRG_parm : {} > B1 PAGE 1 /*Reserved in flash.asm for**/
    /***parameter passing to algos*/
    /*End of sections for flash programming. */
}

```

```

.bss      :{} > B1 PAGE 1
.cinit   :{} > B1 PAGE 1
.const   : load = EXTRAM PAGE 0, run = DSRAM PAGE 1
        {
            /* GET RUN ADDRESS */
            __const_run = .;
            /* MARK LOAD ADDRESS */
            *(.c_mark)
            /* ALLOCATE .const */
            *(.const)
            /* COMPUTE LENGTH */
            __const_length = .- __const_run;
        }
.data    :{} > B1 PAGE 1
.stack  :{} > B1 PAGE 1 /*C stack.          */
}

```

A.6.3 C Function for Disabling TMS320F240 Watchdog Timer

```

*****
*   Watchdog Timer Disable function                               *
*   Arguments passed from Caller: None                          *
*   Local Variables:      None                                  *
*****
SYSSR .set  0701Ah    ; System Module Status Register
WDCR  .set  07029h   ; WDT Control reg
DP_PF1 .set 224      ; 7000h/80h = 100h or 224
        .globl _wdtoff
        .text
        .def _wdtoff
_wdtoff:                ; presume ARP = AR1 (SP)
*****
*   On entry, presume ARP = AR1 (SP)                            *
*   *                                                            *
*   Step 1. Pop the return address off the h/w stack and push to s/w stack *
*****
        POPD *+          ; pop return address, push on software stack
                        ; ARP=AR1, SP=SP+1
*****
*   Step 2. Push the frame pointer onto s/w stack                *
*****
        SAR   AR0,*+     ; push AR0 (FP) onto SP
                        ; ARP=AR1, SP=SP+2
*****
*   Step 3. Allocate the local frame                             *
*****
        SAR   AR1,*      ; *SP = FP
        LAR   AR0,#1     ; FP = size of local frame, 1
        LAR   AR0,*0+    ; FP = SP, SP += size ==> allocate frame
*****
*   Step 5. Begin code that will disable the WDT                *
*****
        LDP #DP_PF1     ; Page DP_PF1 includes WET through EINT frames
        LACL WDCR      ; ACC = WDCR, watchdog timer control register

```

```

        OR    #06fh          ; set WDDIS bit and WDCHK2:0 bits, WDCLK to max.
        SACL  WDCCR         ; write ACC out to WDTCR
*****
*   Step 9. Deallocate the local frame
*****
        SBRK 1+1          ; deallocate frame, point to saved FP
*****
*   Step 10. restore the frame pointer
*****
        LAR  AR0,*-       ; pop FP
*****
*   Step 11. copy the return address from the s/w stack and push onto h/w
*   stack
*****
        PSHD *           ; push return address on h/w stack
        RET              ; return
        .en

```

A.6.4 C Functions for Initializing the TMS320F240

```

*****
*   TMS320x240 Initialization Function
*   Arguments passed from Caller: None
*   Local Variables:           None
*****
SYSSR    .set  0701Ah
SYSCR    .set  07018h
WDTCR    .set  07029h    ;WD Control reg
CKCRO    .set  0702ah    ;PLL Clock Control Register 0
CKCR1    .set  0702ch    ;PLL Clock Control Register 1
DP_PFI    .set  224
        .globl _c240init
        .text
        .def    _c240init
_c240init:    ; presume ARP = AR1 (SP)**
*****
*   On entry, presume ARP = AR1 (SP)
*
*   Step 1. pop the return address off the h/w stack and push to s/w stack
*****
        POPD *+          ; pop return address, push on software stack
                          ; ARP=AR1, SP=SP+1
*****
*   Step 2. push the frame pointer onto s/w stack
*****
        SAR  AR0,*+      ; push AR0 (FP) onto SP
                          ; ARP=AR1, SP=SP+2
*****
*   Step 3. Allocate the local frame
*****
        SAR  AR1,*       ; *SP = FP
        LAR  AR0,#1      ; FP = size of local frame, 1
        LAR  AR0,*0+     ; FP = SP, SP += size ==> allocate frame
*****

```

```

* Step 5. begin code that will initialize the '240 registers *
*****
    CLRC  SXM      ; Clear Sign Extension Mode
    CLRC  OVM      ; Reset Overflow Mode
* Set Data Page pointer to page 1 of the peripheral frame
    LDP #DP_PF1   ; Page DP_PF1 includes WET through EINT frames
* Clear system status register reset bits (PORRST, ILLADR, SWRST, & WDRST)
    LACL #020h    ; load mask pattern to clear rst flags
    SACL SYSSR    ; write ACC to SYSSR
* Set Watchdog timer period to 1 second
    LACL #02Fh    ; set WDCHK2 & 0 bits, WDCLK divider to max (1s)
    SACL WDTCSR   ; write ACC out to WDTCSR
* Configure PLL for 4-MHz xtal, 10-MHz SYSCLK, and 20-MHz CPUCLK
*   SPLK  #00E4h,CKCR1 ;CLKIN(XTAL)=4 MHz,CPUCLK=20 MHz
*   SPLK  #00C3h,CKCR0 ;CLKMD=PLL Enable,SYSCLK=CPUCLK/2
* Configure PLL for 10-MHz osc, 10-MHz SYSCLK, and 20-MHz CPUCLK
    SPLK  #00B1h,CKCR1 ;CLKIN(OSC)=10 MHz,CPUCLK=20 MHz
    SPLK  #00C3h,CKCR0 ;CLKMD=PLL Enable,SYSCLK=CPUCLK/2
* Set VCCAON bit and CLKSRCl:0; leave other bits at their reset values.
    SPLK  #40C8h,SYSCR ; SYSCR <= 40C8h
*****
* Step 9. Deallocate the local frame *
*****
    SBRK l+1      ; deallocate frame, point to saved FP
*****
* Step 10. restore the frame pointer *
*****
    LAR  ARO,*-   ; pop FP
*****
* Step 11. copy the return address from the s/w stack and push onto h/w *
* stack *
*****
    PSHD *        ; push return address on h/w stack
    RET           ; return
    .en

```


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